R&S®RTO6 OSCILLOSCOPE SERIES

Instant insight meets in-depth information

HD 16 bit

Product Brochure
Version 13.00

Oscilloscope innovation. Measurement confidence.
www.rohde-schwarz.com/product/RTO6

ROHDE&SCHWARZ
Make ideas real

THE OSCILLOSCOPE YOU CAN TRUST

R&S®RTO6 OSCILLOSCOPE SERIES

The R&S®RTO6 is the oscilloscope you can trust. Engineered to deliver reliable results, it is a sophisticated laboratory companion to solve measurement problems fast and keep things on schedule. R&S®RTO6 oscilloscopes leverage engineering expertise and improve measurement confidence with deep insights whenever needed.

R&S®RTO6 oscilloscopes provide superior signals for insight into your applications. The large 15.6" touchscreen and streamlined GUI, combined with high waveform update rate, excellent signal fidelity, digital trigger and deep responsive memory serve as a fully integrated test solution for frequency, protocol and logic analysis. The rich measurement toolset for R&S®RTO6 oscilloscopes and streamlined user interface help quickly solve circuit issues, from simple to complex.

A high input sensitivity and very low inherent noise mean that R&S®RTO6 oscilloscopes are optimized to perform precise measurements. High-definition (HD) mode enables easy visualization and triggering on signals with up to 16 bit resolution. R&S®RTO6 oscilloscopes detect and display sporadic signal faults with an industry-leading update rate of up to 1 million waveforms/s.

Today's designs cross multiple measurement domains: time, frequency and protocol. R&S®RTO6 oscilloscopes simplify debugging of systems with different signal types by providing a flexible user interface that allows these domains to be viewed simultaneously. The Rohde&Schwarz digital trigger architecture also enables triggering on complex signal details. This unique trigger system even lets you specify “where” to trigger in the time or frequency domain simply by drawing a special zone directly on the waveform screen.

R&S®RTO6 oscilloscopes are extremely easy to use. The touchscreen-optimized GUI has gesture operations and the R&S®SmartGrid function for complex screen layouts. Setting up intricate measurement tasks is only a matter of dragging waveforms to where they work best for you. The app cockpit provides a one-tap location to access all of the available oscilloscope applications.

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OSCILLOSCOPE PORTFOLIO

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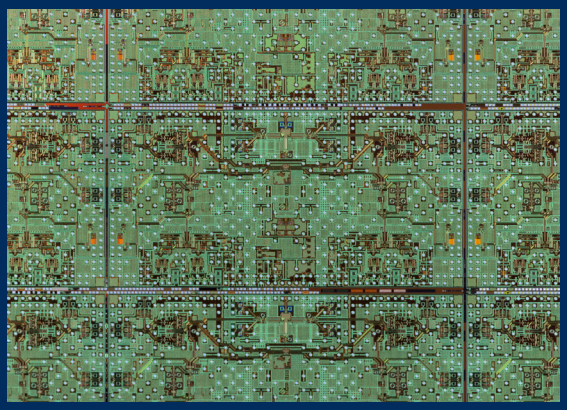
- 6 GHz maximum bandwidth
- 1 million waveforms/s
- 9.4 effective number of bits (ENOB) for ultimate signal integrity
- 2 Gpoints maximum memory
- Exclusive frequency zone trigger

PROVIDING SUPERIOR MEASUREMENTS

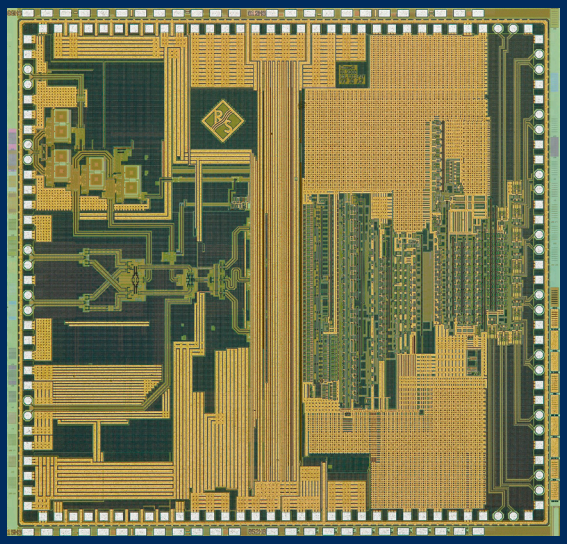
ENABLING TECHNOLOGIES

Rohde & Schwarz oscilloscopes utilize leading-edge technologies to achieve trustworthy and replicable results. Unique components and innovative features are the key for Rohde & Schwarz oscilloscope users to boost the understanding of their circuit behaviors and quickly advance from signal to insight.



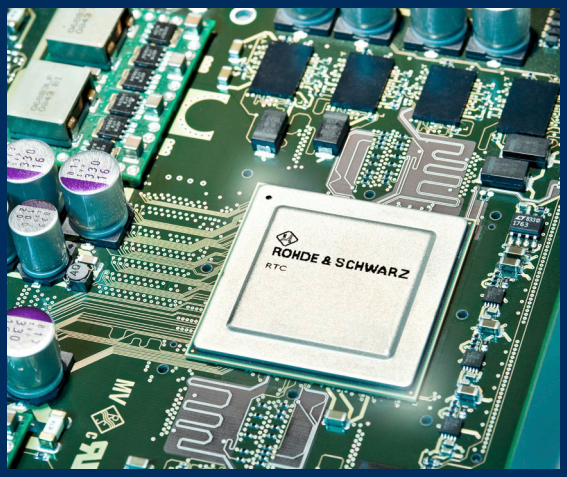
Superior low-noise components

Measurement accuracy is highly dependent on components in a signal path, such as amplifiers, samplers and A/D converters. Rohde & Schwarz has the in-house expertise to design the best analog circuits. Precise measurements benefit from low noise, high measurement dynamic range and extremely stable results.



Outstanding A/D converter

Rohde & Schwarz developed a highly capable A/D converter for R&S®RTO6 oscilloscopes. The sophisticated architecture of this chip minimizes signal distortion and has outstanding vertical resolution and excellent spurious-free dynamic range. The minimized signal distortion is an excellent foundation for precise signal analysis in the optional high-definition (HD) mode. This unique mode further reduces noise, enabling acquisitions and triggers with up to 16 bit resolution.



Fastest throughput ASIC

Every oscilloscope from the R&S®RTO6 series contains an application-specific integrated circuit (ASIC) designed specifically for intensive parallel processing. It processes in real-time during acquisition and quickly prepares a display on the large 15.6" touchscreen. R&S®RTO6 oscilloscopes acquire, analyze and display waveforms with extremely high acquisition rates even while performing measurement and analysis tasks. As a result, these instruments help you find faults significantly faster and more reliably.

FINDING SIGNAL ANOMALIES QUICKLY

WITH UNPARALLELED UPDATE RATES

1 000 000 waveforms/s

The R&S®RTO6 oscilloscope processing path implements a dedicated ASIC. With optimized signal processing, R&S®RTO6 oscilloscopes reach an exceptional update rate. The unique architecture allows the R&S®RTO6 to acquire, process and display up to 1 million waveforms/s.

Available with active histograms, masks or cursor measurements

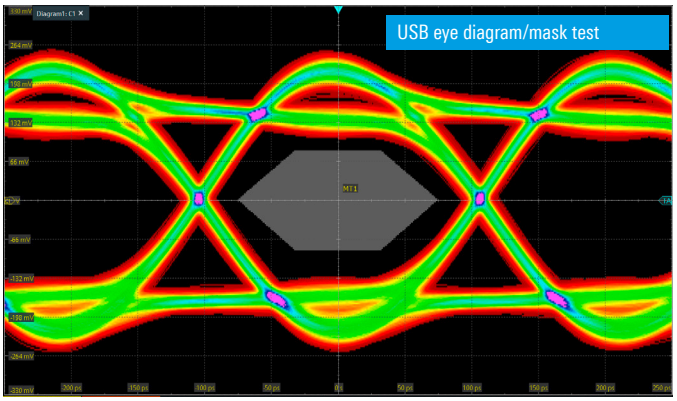
R&S®RTO6 oscilloscopes have a high update rate even when histograms, masks or cursor measurements are active. Also when performing analysis with deep memory acquisitions, the ASIC-based signal processing paths ensure smooth workflows.

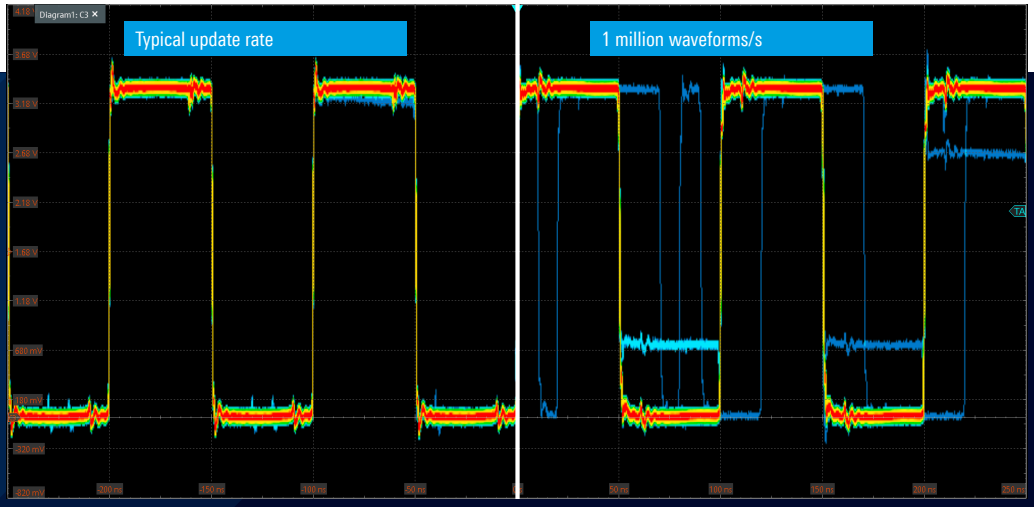
Quickly and reliably detect sporadic signal faults

The statistical confidence in results is higher the more waveforms are acquired. A high update rate increases the likelihood of detecting and displaying signal faults and including them in analysis. The high update rate enables the R&S®RTO6 to generate trustworthy statistical results based on a high number of waveforms in a short time. This is crucial for quickly understanding electronic circuits.

Mask testing: quick configuration and fast results

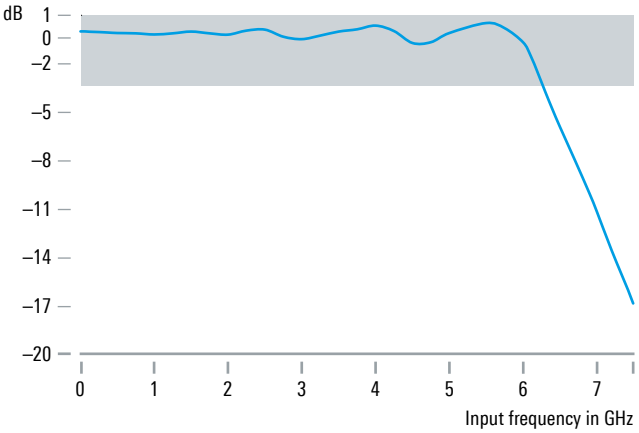
Mask tests quickly reveal whether a specific signal lies within defined tolerance limits, providing pass/fail evaluations for assessing the quality and stability of a device under test (DUT). Signal anomalies and unexpected results are easy to identify. Defining masks is easy and flexible with the R&S®RTO6: just a few touchscreen or mouse gestures, generate a mask from a reference signal or define masks consisting of up to eight segments.





CAPTURING ALL SIGNAL DETAILS
WITH EXCELLENT SIGNAL INTEGRITY

Measured frequency response of the R&S®RTO6



Flat frequency response
For accurate signal acquisition, R&S®RTO6 oscilloscopes have a flat frequency response over the entire specified bandwidth, ensuring accurate measurement results regardless of the signal frequency components. The Gaussian falloff in frequency response leads to low overshoot and precise acquisition of signal edges.

Low-noise frontends and minimized crosstalk
All aspects to minimize noise were considered for both 50 Ω and 1 MΩ input paths, from balanced BNC-compatible inputs with 18 GHz bandwidth to extremely low-inherent-noise frontends. The superb channel-to-channel isolation of > 60 dB up to 2 GHz for R&S®RTO6 oscilloscopes ensures that measurement signals from one channel have the least possible influence on signals in the neighboring channel.

Excellent long-term stability
A reference oven-controlled crystal oscillator (OCXO) optimizes R&S®RTO6 oscilloscopes for long-term stability.

Outstanding A/D converter with ultra-wide SFDR
R&S®RTO6 oscilloscopes incorporate exceptional custom A/D converters with extremely small linearity errors, resulting in an ultrawide spurious-free dynamic range (SFDR) of 65 dBc. This both provides the foundation for excellent signal integrity, while also enabling further noise reduction with HD filtering of R&S®RTO6 oscilloscopes as well as an outstanding 9.4 ENOB.

Excellent shielding to ensure low crosstalk even with high-frequency signals

SEEING MORE
WITH UP TO 16 bit RESOLUTION

16 bit resolution for measuring small signal amplitudes

The high-definition (HD) mode increases the vertical resolution of R&S®RTO6 oscilloscopes up to 16 bit with digital filtering. The increased resolution results in sharper waveforms and reveals more signal details that might be masked by noise. For 16 bit vertical resolution, the signal is lowpass filtered after the A/D converter. Adjusting the lowpass filter bandwidth from 10 kHz to 2 GHz enables matching of the applied signal characteristics: The lower the filter bandwidth, the higher the resolution.

Resolution as a function of the filter bandwidth

Filter	Resolution
Inactive	8 bit
2 GHz [1]	10 bit
500 MHz	12 bit
300 MHz	12 bit
200 MHz	13 bit
100 MHz	14 bit
50 MHz to 10 kHz	16 bit

[1] 2 GHz for 20 Gsample/s, 1 GHz for 10 Gsample/s.

High acquisition rate and full functionality

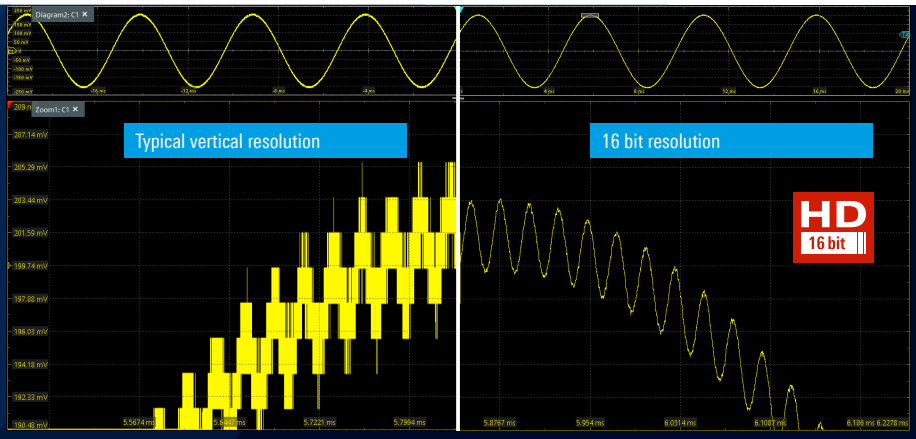
On R&S®RTO6 oscilloscopes, activating the high definition mode does not compromise measurement speed or function. The ASIC signal processing implements lowpass filtering in real-time to maintain high acquisition and processing rates. Oscilloscope operation remains smooth and measurement results are available quickly. All analysis tools are available in HD mode, including automatic measurements and FFT.

Full sample rate: no aliasing

The HD mode offers significant advantages over traditional high-resolution decimation. It increases vertical resolution without reducing sampling rates. Since the HD mode does not decimate data it ensures the best time resolution and does not cause unexpected aliasing effects. It also conveys exactly which signal bandwidth is available thanks to explicit lowpass filtering.

User-selectable filtering: reduced noise, increased ENOB

The HD mode filter reduces the noise in real-time, increasing the signal-to-noise ratio (SNR). The user can choose between Gaussian or brick wall filter characteristics to optimize the oscilloscope step response or noise level. An exceptionally low noise level of 10 µV (1 mV/div, 10 MHz filter bandwidth) is possible as well as outstanding 9.4 ENOB (50 mV/div, 50 MHz filter bandwidth, 30 MHz input frequency) – both at the full sample rate.



FINDING COMPLEX SIGNAL DETAILS

WITH ADVANCED TRIGGER CAPABILITIES

Unique trigger system

The patented digital trigger system uses A/D converter sampling points in the acquisition path, so that input data of the trigger system is identical to the displayed signal. The digital trigger validates every acquired sample against the trigger definition. R&S®RTO6 oscilloscopes trigger even on the smallest signal amplitudes.

High trigger sensitivity at full bandwidth

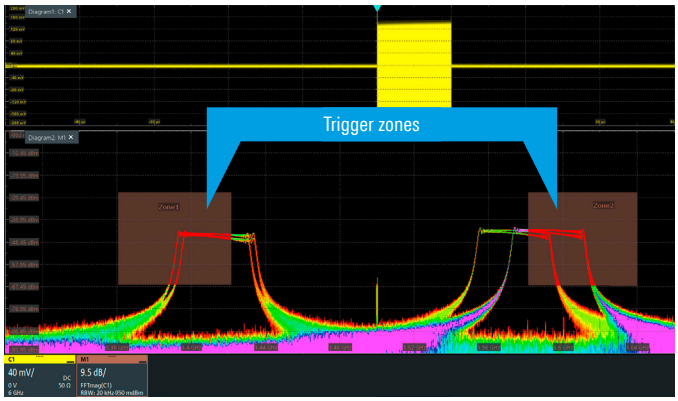
For stable triggering regardless of signal noise levels, the user can set the trigger hysteresis for the oscilloscopes. Due to the low noise frontends, the oscilloscopes can also trigger on signals with high vertical input sensitivities at full measurement bandwidth.

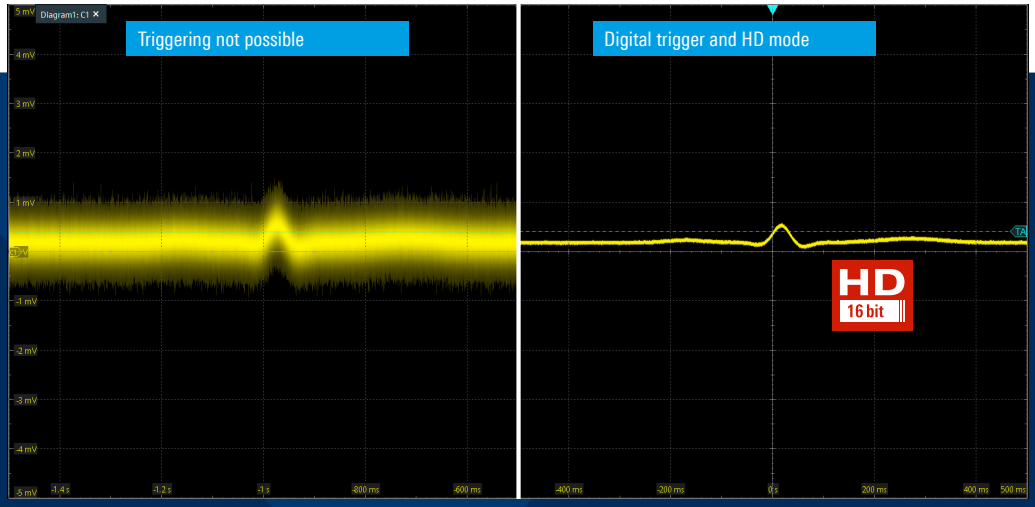
Isolate smallest signal details

R&S®RTO6 oscilloscopes can trigger on even the smallest signal amplitudes and isolate relevant signal events. This capability is possible even when combining the digital trigger and the HD mode, which increases the oscilloscope's vertical resolution up to 16 bit. The digital trigger system checks each of the 16 bit samples against the trigger condition in real-time and can initiate a trigger. This means that R&S®RTO6 oscilloscopes have the best trigger sensitivity in the industry.

Zone trigger in time and frequency domain

Draw shapes on a waveform to have R&S®RTO6 oscilloscopes zone trigger graphically separate events in both the time and frequency domains. Define up to eight zones and logically combine them over multiple channels or math functions. Zones activate a trigger signal when a signal either intersects or does not intersect the zone which can be a real-time waveform or a spectrum plot. For example, this powerful, yet easy-to-use feature makes it possible to separate read/write sequences from a DUT memory system.



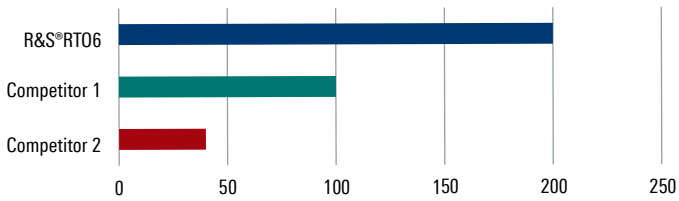


MEASURING MORE
WITH DEEP AND RESPONSIVE MEMORY

Maximized memory: 200 Mpoints standard, 2 Gpoints optional

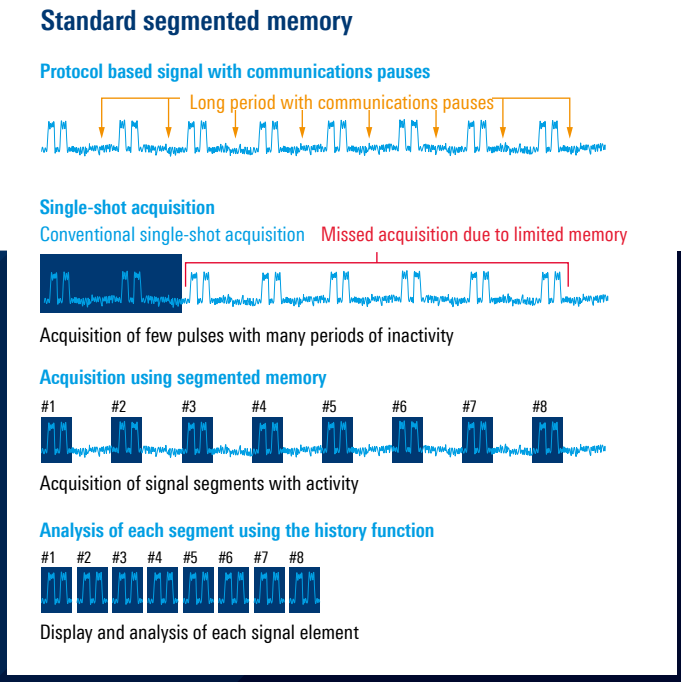
The basic configuration of R&S®RTO6 oscilloscopes offer 200 Mpoints acquisition memory per channel. Applications such as seamless acquisition of long pulse or protocol sequences often require even deeper memory. The R&S®RTO6 oscilloscope acquisition memory can be extended up to 2 Gpoints. Even with deep memory acquisitions, ASIC signal processing ensures a smooth workflow.

Acquisition time in ms (at 10 Gsample/s)



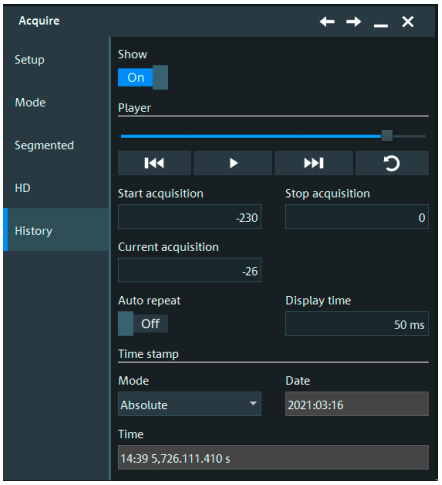
Segmented memory to capture distant trigger events

Standard segmented memory analyzes signal sequences over a long observation period, capturing protocol-based signals with communications gaps such as I²C and SPI over extended periods without wasting storage on idle time. Thanks to a variable segment size, the deep memory is optimally utilized and numerous consecutive individual segments are possible. The segmented memory of the R&S®RTO6 lets you capture more than 100 000 timestamped acquisitions.



History mode to analyze previous trigger events

The always-on history function of R&S®RTO6 oscilloscopes ensures access to waveforms previously stored in the memory. A trigger timestamp enables straightforward time correlation. You can view and analyze all captured signals with the zoom, measurement, math and spectrum analysis functions.



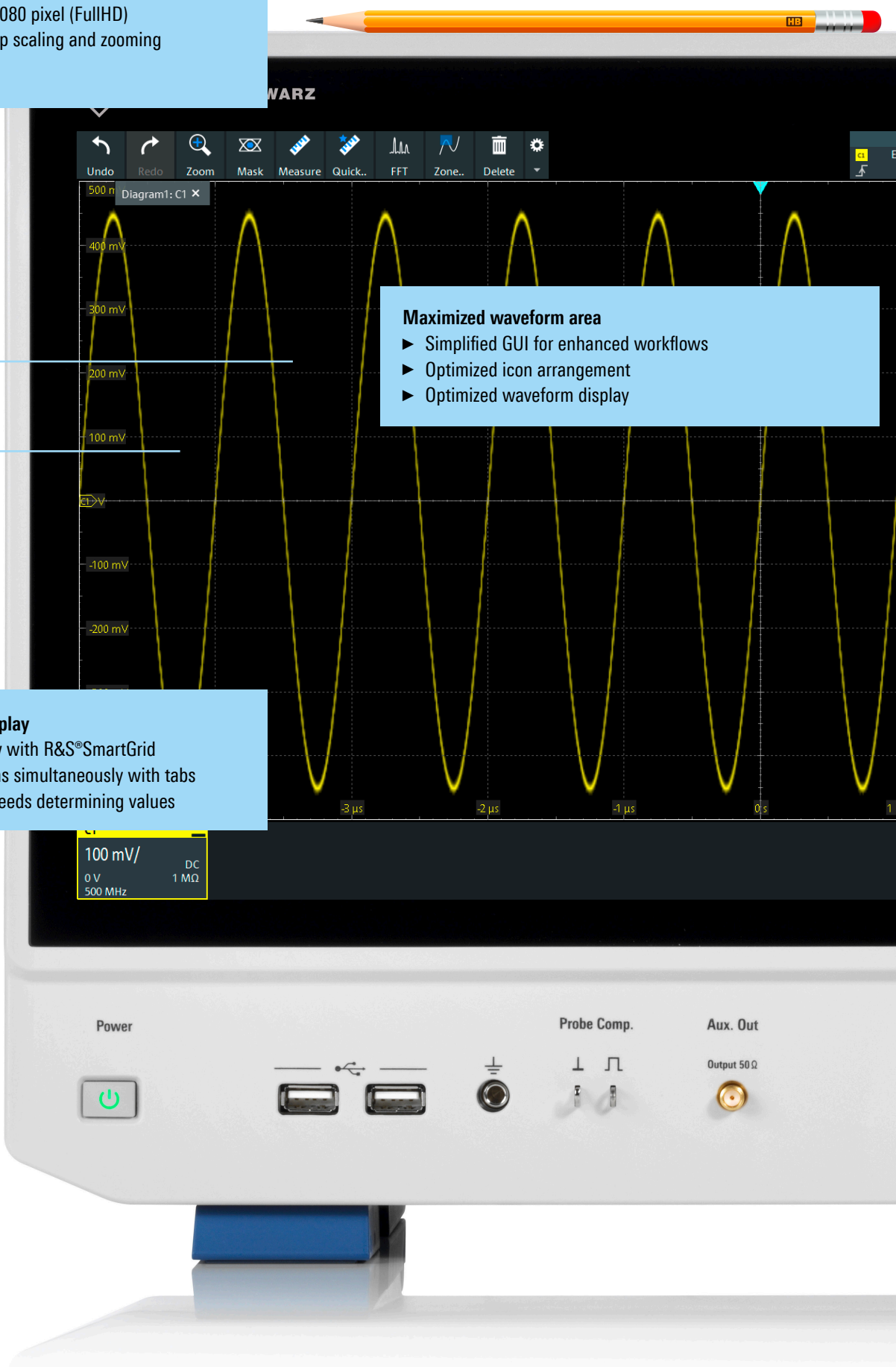
Search and navigation: find faults fast

Comprehensive search functions simplify the analysis of long signal sequences. Search for waveforms based on different criteria, such as signal fault, signal pattern and protocol contents. Search on analog or digital channels, on reference or math waveforms and on serial, protocol-based buses as needed for your specific applications. An easy-to-read table shows all detected events with timestamps. Examine the individual events in a zoom window and navigate between them. View details such as the number of glitch errors in a table and have each individual glitch in the waveform correlated with other signals.

ENHANCED USABILITY

15.6" high-resolution capacitive touchscreen

- High resolution: 1920 × 1080 pixel (FullHD)
- Gesture support speeds up scaling and zooming
- Easy to see signal detail



Maximized waveform area

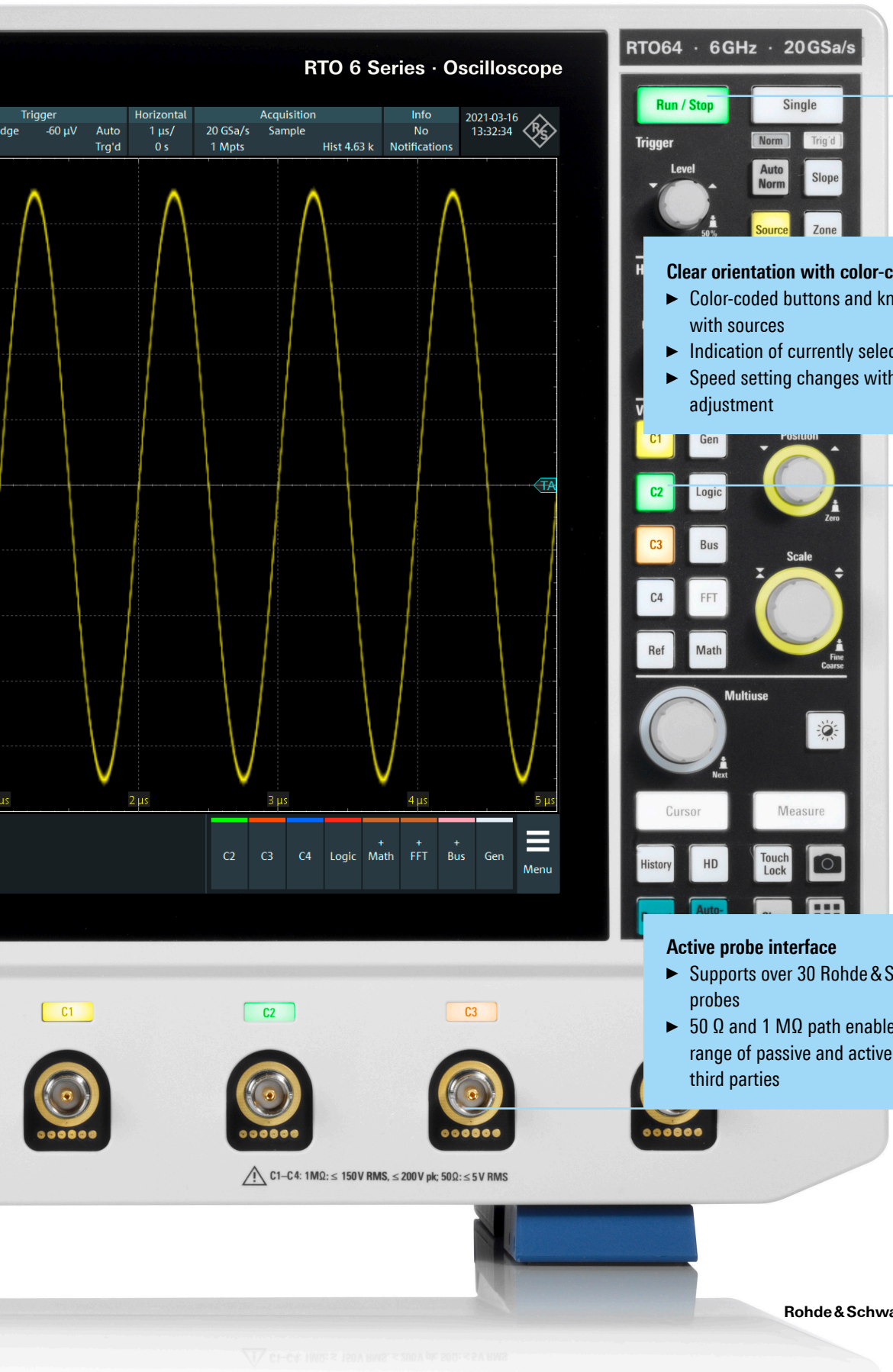
- Simplified GUI for enhanced workflows
- Optimized icon arrangement
- Optimized waveform display

Customizable waveform display

- Quickly arrange your view with R&S®SmartGrid
- Manage multiple diagrams simultaneously with tabs
- Axis scales annotation speeds determining values

Intuitive front panel increases user productivity

- Fast, direct access to primary instrument settings
- Quickly adjust settings with knobs and buttons
- Sectional layout makes finding the right button easy



Clear orientation with color-coded LEDs

- Color-coded buttons and knobs enable fast association with sources
- Indication of currently selected channel
- Speed setting changes with fine/course pushable adjustment

Active probe interface

- Supports over 30 Rohde & Schwarz current and voltage probes
- 50 Ω and 1 MΩ path enable support of an even wider range of passive and active probes, including ones from third parties

SUPERIOR USER EXPERIENCE

ADVANCED USABILITY, EASY DOCUMENTATION, FAST REMOTE CONTROL

Quick access to important tools

The toolbar 1 enables quick access to important tools. Here you can directly set the most common parameters in a simple overlay menu, including FFT start/stop, span and RBW 2. Choose from 28 different tools for maximum flexibility. The upper menu also displays trigger, horizontal and acquisition settings 3.

Advanced setup with compact menu structure

An advanced setup 4 is available for tools where detailed parameters can be defined, such as FFT window type and span/RBW coupling. The compact menu structure allows you to directly see the impact of measurement modifications.

Signal bar and preview icons

Activated signals appear in the flexible R&S®SmartGrid 5, along with the fundamental signal parameters displayed in the signal bar 6. From here, drag & drop into the R&S®SmartGrid for an individual waveform layout. A signal preview is also available in the signal bar for minimized signals 7.

Signal activators and main menu

Signals activators 8 turn on different signals with just one touch/click (analog channels, math, FFT, serial protocols, signal generator), making possible the straightforward configuration of your measurement setup. The main menu provides access to all instruments settings.

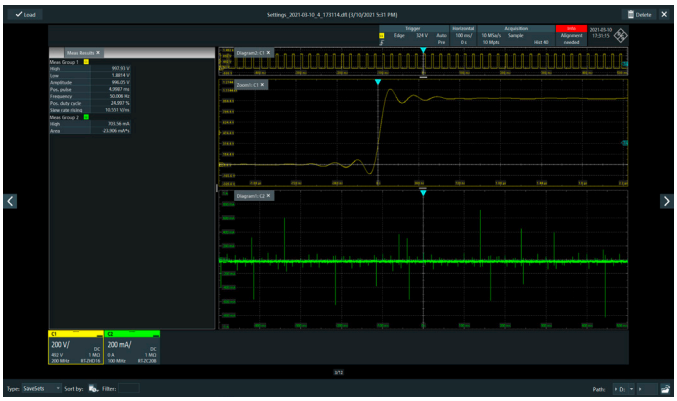
Save results fast

Save waveforms in various file formats or download them via Ethernet for later analysis with MATLAB or Excel. Continuous acquisition, analysis and transmission to a PC via Ethernet is possible with 100 waveforms/s. You can also save screen content or print it directly from the oscilloscope.

Documentation at the press of a button

Document your measurements quickly:

- Screenshots include waveforms and results
- Reports include screenshots and instrument setup
- Clear grid annotations make for easy-to-read signal characteristics
- Color-coded labels highlight anomalies in the diagram
- Save waveforms, histograms and measurement results in binary, XML or CSV formats are available for signal analysis on a PC



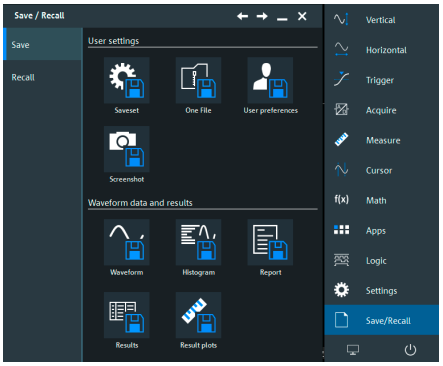
Remote control access: anytime, anywhere

Remotely control the oscilloscope and view the display on a PC or mobile device. View the same user interface on the oscilloscope. All oscilloscope functions are also available remotely via Ethernet, GPIB or the USB interface.

Storage options		
Onefile	complete	stores waveform, setup, math channels, reference waveforms in one zip file
Contents	waveform	complete
		selection (zoom, cursor, gate, manual)
		number of acquisitions
		history memory
Evaluation		histograms
		measurement results
		long-term trend
Format	measurement data	binary, XML, CSV, 1 to 4 channels
	graphics	PNG, JPG, BMP, TIF, PDF
	reports	PDF, HTML, DOC
Drivers		VXi, LabView, LabWindows, .NET

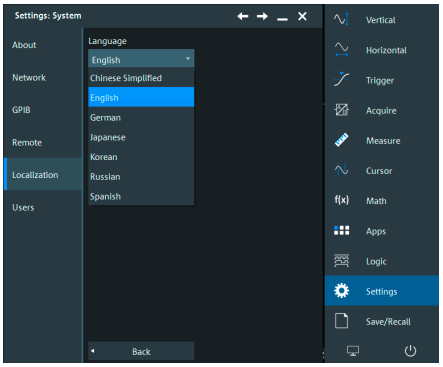
Easy selection of instrument setup

Each save set is stored along with an instrument setup including a screenshot of the most recent oscilloscope display. To open a specific instrument setup later, simply scroll through the screenshots to find the right configuration.



Language selection

The R&S®RTO6 oscilloscope user interface supports multiple languages. Just a few seconds are needed to switch languages while the instrument is running, making the oscilloscope truly international.



TACKLING NOVEL, COMPLEX ISSUES

COMPREHENSIVE TOOLS FOR FAST AND ACCURATE RESULTS

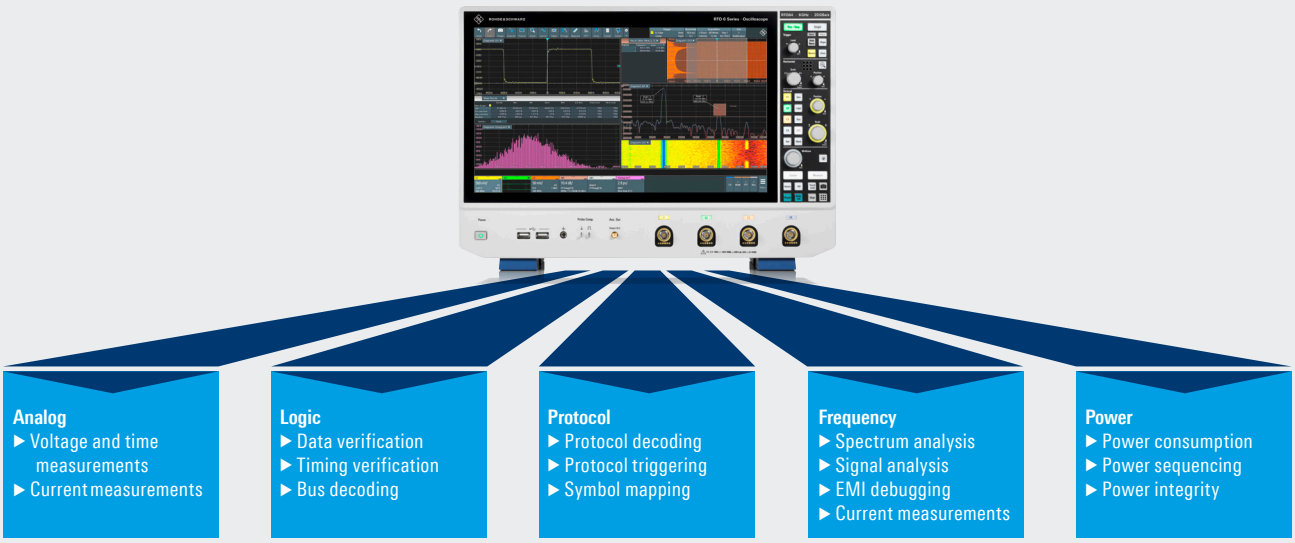
- **Hardware-accelerated measurement functions and math operations**
- **Wide range of basic analysis functions**
- **Multi-instrument capabilities**
- **Industry-leading zone trigger and mask testing**
- **Application-specific software options**

Time-correlated analysis of multiple signal types

R&S®RTO6 oscilloscopes address various test requirements for highly integrated devices. They combine multiple test instrument capabilities in a single box:

- The analog channels offer superior signal fidelity and fast measurements, with limit tests and histograms as well as hardware-accelerated mask testing.
- General purpose resources, such as the standard enabled digital channels (MSO) or the arbitrary waveform generator, allow logic analysis and/or protocol-based testing of serial buses, including symbolic decoding and advanced bus analysis.
- The R&S®RTO6 provides comprehensive tools for fast and detailed signal analysis in the frequency domain and shows correlation with the time domain.

R&S®RTO6 oscilloscope offers multiple test instruments in one



Rich debugging toolset

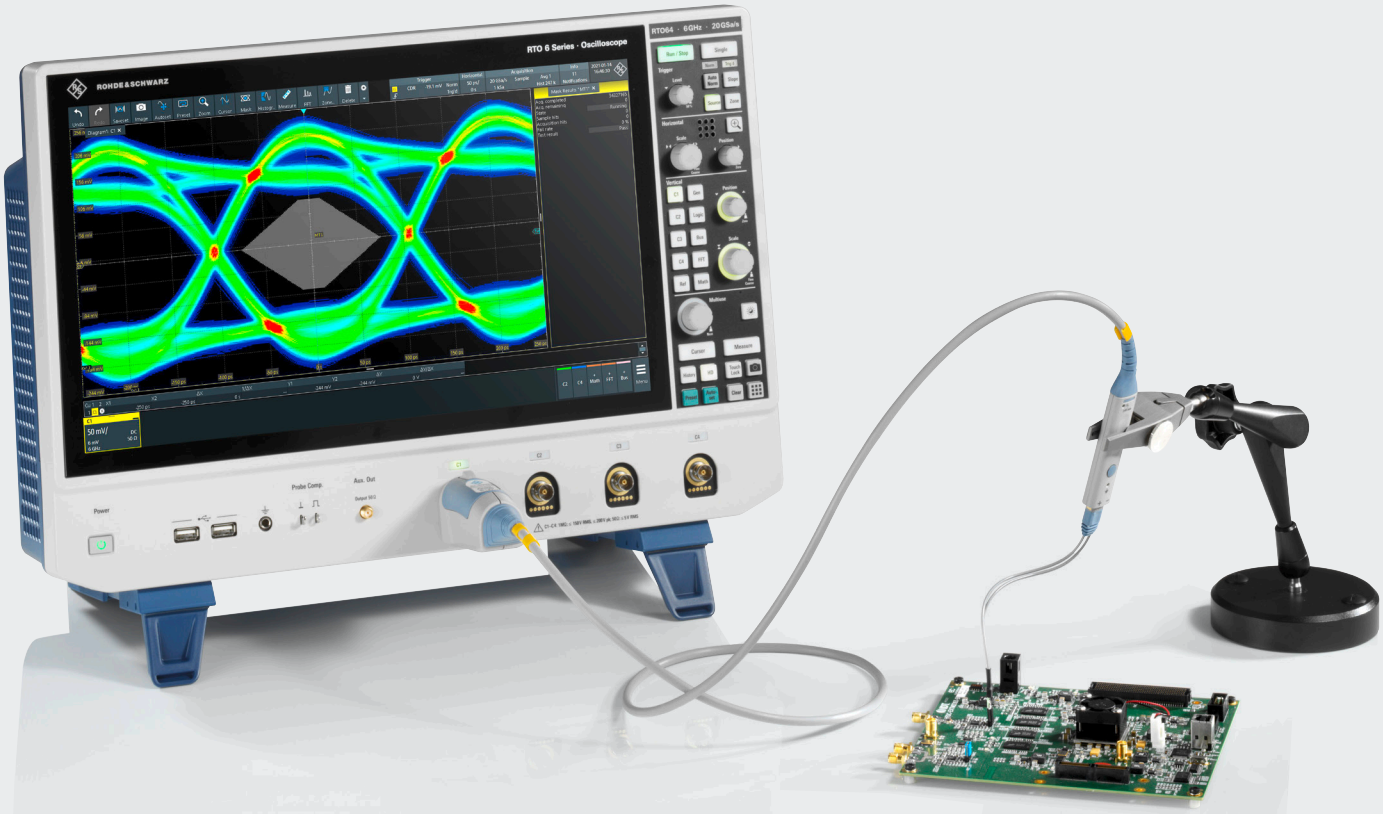
Every R&S®RTO6 oscilloscope has over 90 measurement functions. They are organized by type into amplitude, time, jitter, eye, histogram and spectral measurements. Statistics, histograms, trend and track functions facilitate detailed analysis of measurement results. These results can also be used in math functions.

Available signal analysis functions	
Statistics	display of average value, minimum/maximum value and standard deviation
Histogram	graphic display of events as histogram; definition of measurement range and resolution for histogram (manual or automatic)
Trend	long-term trend function for analyzing slowly developing variations in measurement results (easy identification of thermal dependencies within measurement results)
Track	analysis of rapidly changing measurement results in time periods; display results over entire acquisition period
Gating	restriction of the measurement range to a specific signal range (manually defined or linked to existing cursor or zoom ranges)
Reference lines	definition of reference lines (manual, automatic or averaged); optional display in the waveform
Waveform	graphic display of results on waveform, e.g. for documentation
Multiple measurements	definition of the maximum number of measurements per waveform

Application-specific software for your technology

R&S®RTO6 oscilloscopes have a multitude of application-specific software options to tailor your oscilloscope to your application needs and provide in-depth capabilities for all your different tasks, ranging from general signal and spectrum analysis to more complex assignments such as jitter decomposition and TDR/TDT analysis. The software options are also available after purchase with a simple keycode upgrade.

Analysis options	
I/Q interface	R&S®RTO6-K11
Clock data recovery	R&S®RTO6-K13
Power analysis	R&S®RTO6-K31
Spectrum analysis	R&S®RTO6-K37
User-defined math with Python	R&S®RTO6-K39
Deembedding	R&S®RTO6-K121
Embedding and equalization	R&S®RTO6-K126
TDR/TDT analysis	R&S®RTO6-K130
Jitter analysis	R&S®RTO6-K12
Advanced jitter	R&S®RTO6-K133
Advanced noise	R&S®RTO6-K134
PAM-N analysis	R&S®RTO6-K135
Advanced eye analysis	R&S®RTO6-K136



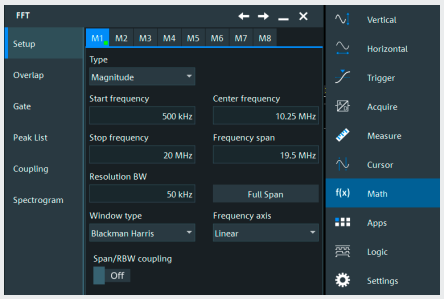
SPECTRUM ANALYSIS

RF knowledge in an oscilloscope

- **Multichannel spectrum analysis (up to eight in parallel)**
- **Zone trigger for time and frequency domain**
- **Gated FFT for easy frequency and time correlation**
- **Spectrogram displays changes in spectrum over time**
- **Better and faster insights: logarithmic display and peak list**

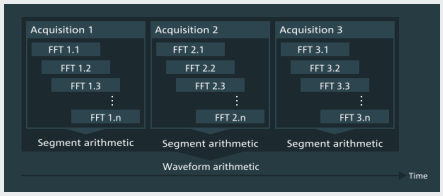
Set up as a spectrum analyzer

Operate the R&S®RTO6 frequency analysis function like a spectrum analyzer. Simply enter the typical parameters: center frequency, span and resolution bandwidth. Select the window type, FFT overlap, gating and logarithmic or linear Y-axis scaling based on application requirements.



Overlap FFT

The R&S®RTO6 oscilloscope's overlap FFT splits the captured time-domain signal into overlapping segments and calculates an individual spectrum for each segment. These spectra are then compiled and combined to a complete spectrum with color-coding that corresponds to the frequency of occurrence. The complete spectrum provides a very good overview of the type and recurrence of different frequency emissions. Even sporadic signals are visible.

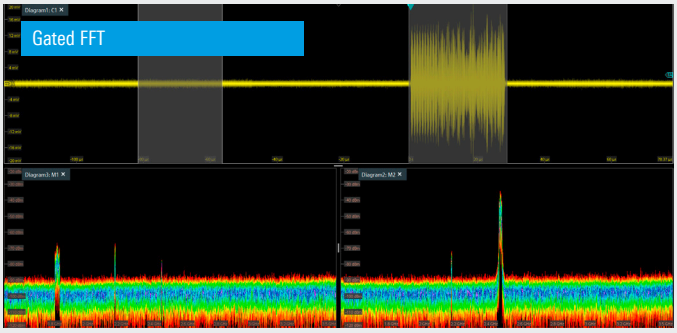


Multiple FFTs with outstanding RF performance

R&S®RTO6 oscilloscopes support powerful multichannel spectrum analysis for up to eight signals in parallel. Their high dynamic range and input sensitivity of 1 mV/div at full measurement bandwidth make it possible to detect even weak emissions. The powerful FFT implementation is ideal for required analysis in the frequency domain thanks to its easy operation, high acquisition rate and functions such as color-coding of the spectral display according to the frequency of occurrence.

Gated FFT: frequency and time correlation

The R&S®RTO6 oscilloscope gated FFT function applies FFT analysis only to user-defined regions of the acquired time domain signal. Users can move the time window across the entire waveform to determine which segments of the time domain signal correlate to certain events in the spectrum. This makes it possible to correlate unwanted emissions from switched-mode power supplies with overshoots from the switching transistor.



Spectrogram: display changes in power and frequency over time

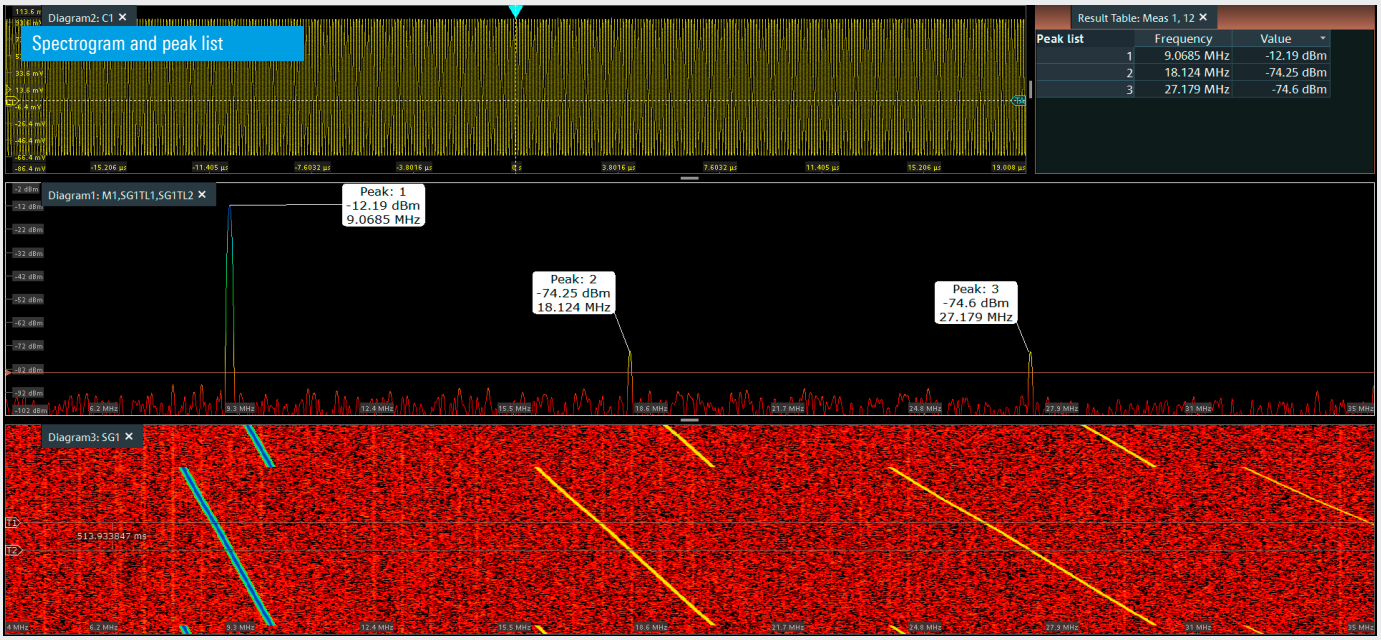
The R&S®RTO6 spectrum analysis option is ideal for analyzing time varying signals in the frequency domain. Its spectrogram is a color-coded frequency-timing diagram that displays the spectral power over time. It indicates how the spectrum varies over time in a two-dimensional intensity diagram. R&S®RTO6 oscilloscopes allow you to quickly analyze voice and AM/FM modulated signals as well as signals from radar and frequency-hopping systems.

Frequency analysis with logarithmic display

The R&S®RTO6 oscilloscope spectrum analysis option enables logarithmic frequency scaling for spectrum and spectrogram displays.

Fast results with automatic peak list measurement

The peak list measurement automatically detects peaks in the FFT spectrum and indicates their magnitude and frequency in the spectrum graph and in a result table.



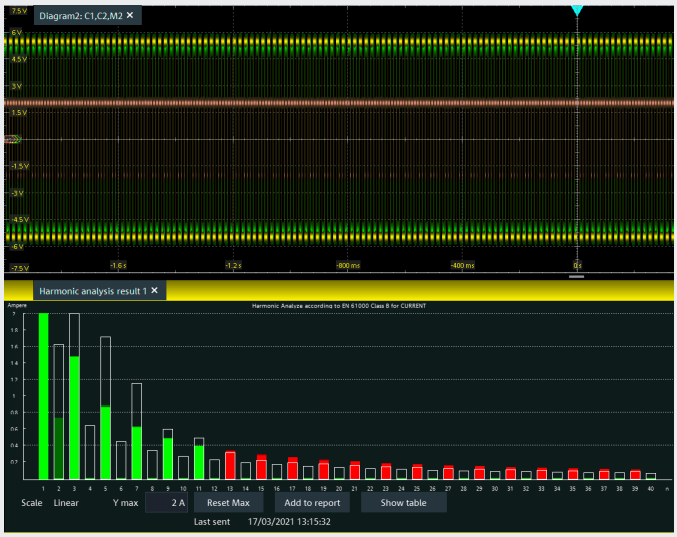
POWER ANALYSIS AND EMI DEBUGGING

Engineered for power and EMI measurements

- **See power signal details with up to 16 bit resolution**
- **Maintain fast sampling rates with deep memory**
- **Visualize sporadic emissions**
- **Specialized measurement functions: fast and accurate results**
- **Extensive probe portfolio: high voltage and current probes**

See power signal details with up to 16 bit resolution

Even the smallest signal details of a high dynamic signal matter in power measurements, for example when verifying RDS_{on} of a MOSFET. The HD mode of R&S®RTO6 oscilloscopes increases the vertical resolution to up to 16 bit, so that previously unseen signal details become visible and measurable.



Specialized measurement functions and harmonic current analysis

Characterize power electronics with the R&S®RTO6 oscilloscope power analysis option. Automated measurement functions analyze the turn on/off behavior, the internal transfer function, the safe operating area (SOA), the output signal quality and switching losses. You can also test all common international standards.

Maintaining fast sampling rates with deep memory

Analyzing start-up, shut-down or transients of power supplies requires a high sample rate and long recording times. With up to 1 Gpoints memory, R&S®RTO6 oscilloscopes enable recording of lengthy sequences while maintaining high sampling rates of up to 20 Gsample/s.

Power measurement functions	
Input	quality, inrush current, harmonics (precompliance checking for IEC 61000-3-2 (A, B, C, D), RTCA DO-160, MIL-STD-1399)
Switching/control loop	slew rate, modulation, dynamic on-resistance
Power path	efficiency, loss, safe operating area (SOA), turn on/off
Output	ripple, spectrum (double-logarithmic scale), transient response
Deskew	automated

Detect weak emissions with high dynamic range and input sensitivity

The high dynamic range and input sensitivity of 1 mV/div at full measurement bandwidth make it possible to detect even weak emissions with R&S®RTO6 oscilloscopes. The powerful FFT capabilities are ideal for EMI analysis in the frequency domain thanks to their easy operation, high acquisition rate and manifold functions, such as color coding of the spectral display according to frequency of occurrence.

Extensive analysis for EMI debugging

The mask trigger in the frequency domain is ideal for detecting sporadic emission frequencies. The stop-on-violation condition halts acquisition if the spectrum violates the frequency mask. The gated FFT capability provides better insight by displaying the time and frequency domain correlation over a user-defined window.

Probes for high voltage, current and near-field measurements

The Rohde & Schwarz oscilloscope probe portfolio includes specific probes for power measurements and EMI debugging. The portfolio covers high voltage probes and differential probes for voltages up to 6000 V (peak) with exceptional common mode rejection ratios over a broad frequency range, as well as current probes for accurate, non-intrusive measurements of DC and AC currents in the range of 1 mA to 2000 A with a maximum bandwidth of up to 120 MHz. E and H near-field probes are available for the frequency range from 9 kHz to 3 GHz with optional preamplifier for EMI debugging.

POWER INTEGRITY

Debugging and validating power rails

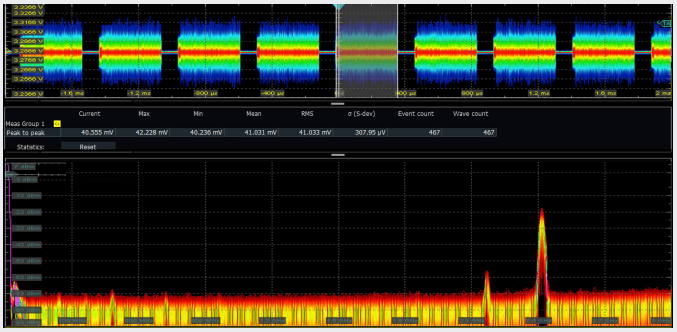
- **Accurately measure power ripple and PARD**
- **Find coupled sources with fast FFT**
- **Power rail characterization with high-fidelity probes**
- **Large DC offsets and integrated high precision DC voltmeter**

Accurately measure ripple and PARD

As power rail tolerance levels decrease, accurately measuring power ripple becomes increasingly difficult. The inherent low noise of R&S®RTO6 oscilloscopes enables accurate power integrity measurements at the millivolt level. The fast update rate of the oscilloscopes allows you to quickly see infrequent and worst case ripple as well as periodic and random disturbance (PARD) anomalies.

Measuring small voltages riding on large DC offsets

With the ±60 V offset compensation range, the R&S®RT-ZPR power rail probes allow you to focus on small ripples in the power rail DC voltage. Whether you need to zoom in on a 1 V or much higher DC level, the probe provides the required offset while maintaining the highest vertical resolution.



Find coupled sources

The most capable FFT in the industry lets you can see switching characteristics or quickly scan for sources coupled with the power rail. The FFT algorithm allows you to analyze the spectrum independently of the time domain settings. This provides a quick and comprehensive picture of your power rails.

R&S®ProbeMeter: integrated voltmeter for precise DC measurements

The R&S®ProbeMeter lets you see the oscilloscope waveform and DC value regardless of other instrument settings, just like a highly accurate voltmeter. All voltage probes with Rohde&Schwarz probe interfaces support the R&S®ProbeMeter.

Power rail characterization with high fidelity probes

High bandwidth, high sensitivity, very low noise and an extra-large offset compensation make the R&S®RT-ZPR an excellent probe for characterizing power rails. With a bandwidth of up to 4 GHz, excellent sensitivity thanks to the 1:1 attenuation ratio and low noise, the R&S®RT-ZPR is ideal for precise ripple measurements. Coupled with the powerful frequency analysis capabilities of the oscilloscope, R&S®RT-ZPR probes can be used to isolate PARD. An integrated high-precision DC voltmeter provides an instantaneous DC voltage readout in parallel.

SERIAL BUS ANALYSIS

Easy triggering, decoding and protocol analysis

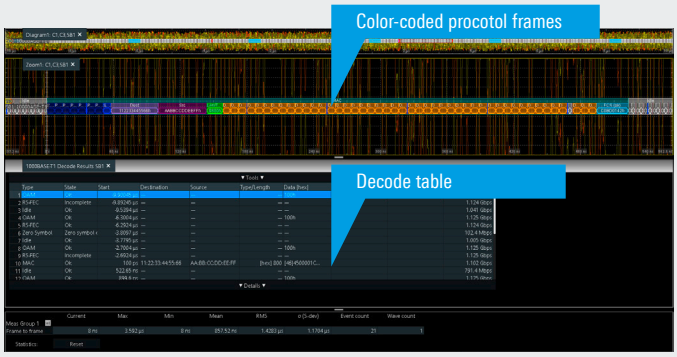
- **Hardware-based triggering and decoding for fast analysis**
- **Decoding of up to four serial buses simultaneously**
- **Advanced bus measurements for in-depth analysis**
- **Search functions for easier analysis of long and complex signals**

Isolate protocol specific events

The R&S®RTO6 makes tracking down protocol errors or specific parts of a frame straightforward with a protocol aware trigger. The oscilloscope offers hardware-based triggering on specific protocol content, such as addresses, data and protocol errors.

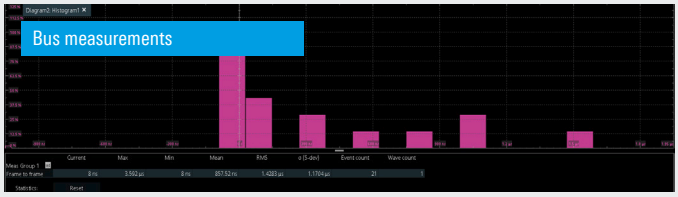
High acquisition rate for finding errors quickly

Data errors on serial interfaces are frequently the result of sporadic signal faults from borderline timing of logic components. The high acquisition rate of R&S®RTO6 oscilloscopes is ideal for finding such signal faults because they decode the protocol-specific trigger results very quickly. So, errors are swiftly found and immediately displayed.



Advanced bus measurements

R&S®RTO6-K500 bus measurement option enables in-depth analysis of decoded data. For example, you can quickly determine the stability of a bus by detecting the frame error rate including consecutive frame errors. Analyze bus timing by measuring the delay between frames or between any trigger event and the bus frame.



Fast and efficient data search

Comprehensive search and filter functions simplify analysis of long signal sequences. They permit users to quickly track down specific data types, content and errors. All detected events are shown in a table with timestamps. The user can then examine the individual events in a zoom window with associated timing correlation and navigate between events.

Segmented memory for long time capture

Standard segmented memory is ideal for serial protocols. It allows you to capture only the relevant packets and ignore the long idle time in between packets. The R&S®RTO6 can capture more than 100 000 timestamped packets.

Trigger and decode packages		Supported protocols
R&S®RTO6-K500	bus analysis	I²C, SPI, UART, CAN/CAN FD, LIN, SENT, Ethernet (10BASE-T/100BASE-TX), RFFE, Automotive Ethernet (100BASE-T1/1000BASE-T1)
R&S®RTO6-K510	low speed serial buses	I²C/SPI/RS-232/UART/I²S/LJ/RJ/TDM/Manchester/NRZ
R&S®RTO6-K520	automotive protocols	CAN/CAN XL/LIN incl. CAN-dbc file import/CAN FD, FlexRay incl. Fibex file import/SENT/CXPI
R&S®RTO6-K530	aerospace protocols	MIL-STD-1553/ARINC 429/SpaceWire
R&S®RTO6-K540	Ethernet protocols	10BASE-T/100BASE-TX/MDIO
R&S®RTO6-K550	MIPI low speed	MIPI RFFE, I³C
R&S®RTO6-K560	automotive Ethernet	IEEE 10BASE-T1S/100BASE-T1/1000BASE-T1
R&S®RTO6-K570	USB protocols	USB 1.0/1.1/USB 2.0/HSIC/USB 3.1 Gen 1, USB Power Delivery (USB-PD)/USB SSIC
R&S®RTO6-K580	MIPI M-PHY, D-PHY	MIPI D-PHY/M-PHY/UniPro/decoding for DSI und CSI-2
R&S®RTO6-K590	PCI Express	8b10b (up to 6.25 Gbit/s)/ PCI Express Revision 1.x/2.x
R&S®RTO6-TDBDL	trigger and decode bundle	R&S®RTO6-K500/-K510/-K520/-K530/-K540/-K550/-K560/-K570/ -K580/-K590

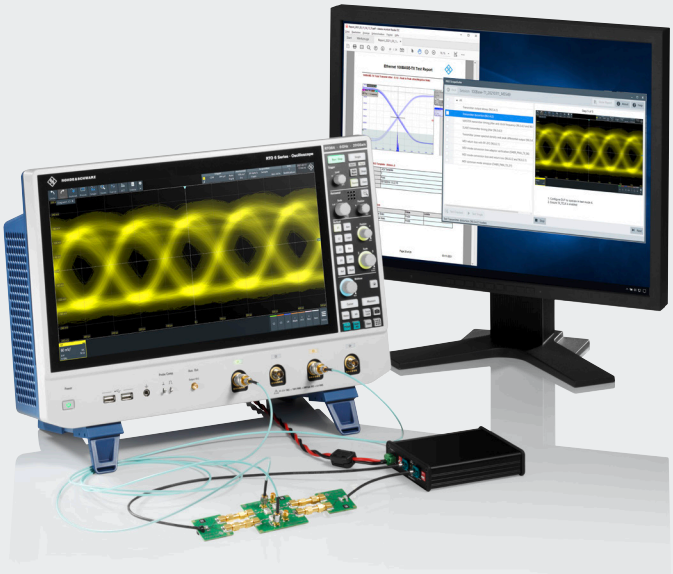
AUTOMATED COMPLIANCE TESTS

Validate your design

- **Easy configuration and automatic control**
- **Flexible test execution**
- **Straightforward, configurable reports**

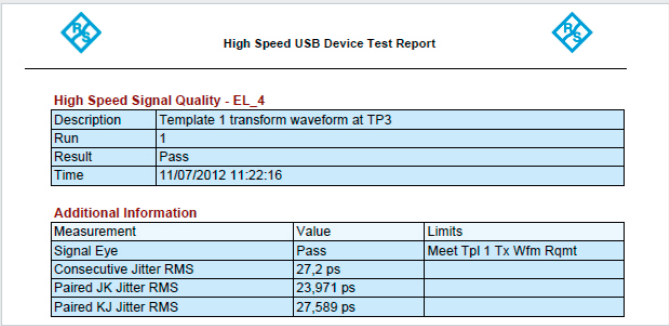
Easy configuration and automatic control

R&S®ScopeSuite is a generic compliance test software that runs on the R&S®RTO6 oscilloscope or separate PC. It controls the measurement settings and test sequences on the oscilloscope and guides you through all the selected tests based on the test setup. Detailed instructions make it easy to correctly connect the oscilloscope and probes to the test fixture and DUT. User data, the test setup settings and measurement report definitions are easy to configure. The limit editor lets you individually adjust standard-specific test limits.



Straightforward, configurable reports

Documenting the measurement results is essential to compliance tests. R&S®ScopeSuite offers an extensive range of documentation functions. You can add measurement details and screenshots to the pass/fail results. Available output formats are PDF, DOC and HTML.



High Speed USB Device Test Report

High Speed Signal Quality - EL_4

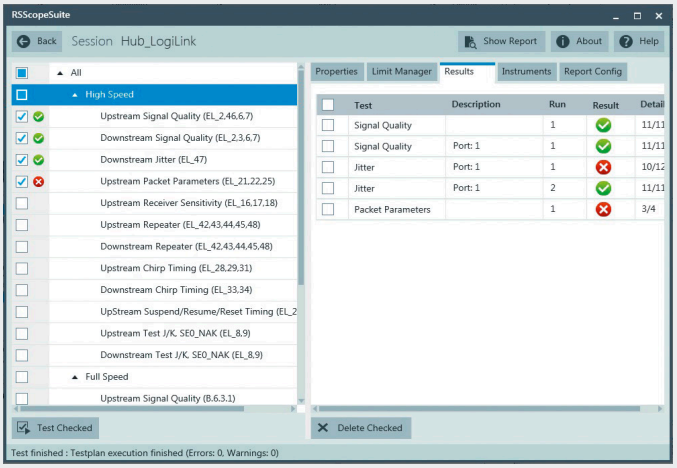
Description	Template 1 transform waveform at TP3
Run	1
Result	Pass
Time	11/07/2012 11:22:16

Additional Information

Measurement	Value	Limits
Signal Eye	Pass	Meet Tpl 1 Tx Wfm Rqmt
Consecutive Jitter RMS	27,2 ps	
Paired JK Jitter RMS	23,971 ps	
Paired KJ Jitter RMS	27,589 ps	

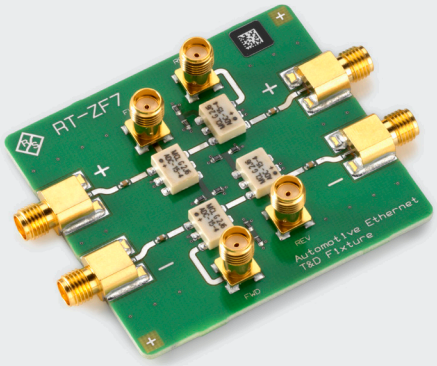
Flexible test execution

For debugging during development or stability tests, you can repeat single tests or a sequence of tests as often as required. Between single tests, you can change limit lines or other parameters for every test and compare their impact on the results. For documentation, R&S®ScopeSuite generates a test report from the selected test results.



Test fixture sets from Rohde & Schwarz

Rohde & Schwarz offers test fixture sets in line with the different interface standards to connect the measuring equipment and the DUT.



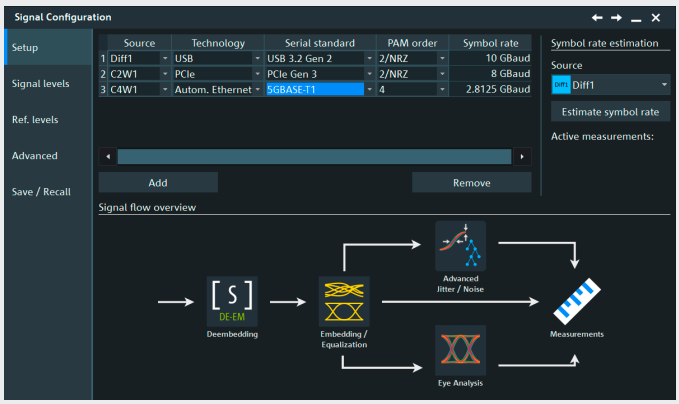
Compliance option	Included protocol
R&S®RTO6-K21	USB2.0
R&S®RTO6-K22	10M/100M/1G-BASE-T/EE Ethernet
R&S®RTO6-K23	2.5/5/10G-BASE-T Ethernet
R&S®RTO6-K24	100BASE-T1 Ethernet
R&S®RTO6-K26	MIPI D-PHY
R&S®RTO6-K27	MIPI D-PHY 2.5
R&S®RTO6-K81	PCIe 1.1/2.0 (up to 2.5 GT/s)
R&S®RTO6-K87	1000BASE-T1 Ethernet
R&S®RTO6-K88	MGBASE-T1
R&S®RTO6-K89	10BASE-T1 Ethernet
R&S®RTO6-K91	DDR3/DDR3L/LPDDR3
R&S®RTO6-K92	eMMC

SIGNAL INTEGRITY ANALYSIS

Analyzing the whole signal path

Signal configuration

The signal configurator is the central entry point for signal integrity analysis. Interface standards based on configurations, such as symbol rate, PAM order, CDR settings and equalizer coefficients are supported. Just select an input channel as source, the appropriate standard and configure deembedding, embedding and equalization, before starting an in-depth analysis with automated measurements, eye,jitter and noise tools.



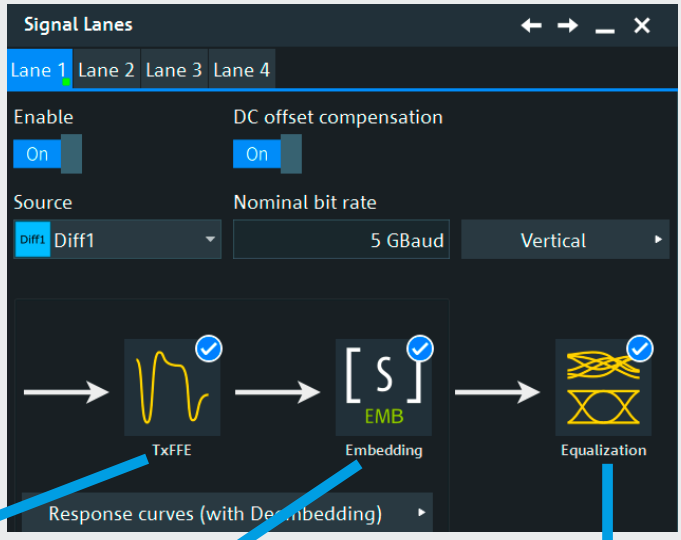
Signal configurator: select the appropriate interface standard for preconfiguration of CDR or equalizer parameters

Emulation of channel loss and TX/RX equalization

A high speed signal travelling through a transmission channel composed of chip housing, PCB traces, vias, connectors or cables will experience distortion. Different test points are typically defined or accessible for thorough signal analysis along the transmission channel. Common transmitter and receiver characteristics can be emulated by embedding dedicated channel loss and applying an adequate equalization filter.

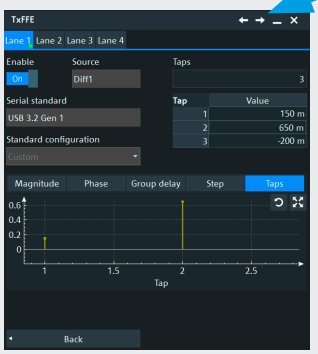
The R&S®RTO6 lets a signal lane be flexibly configured to match the characteristics of a DUT and its target application. The R&S®RTO6 automatically computes FIR filters based on the loaded S-parameter files for embedding and the defined coefficients for the equalizers.

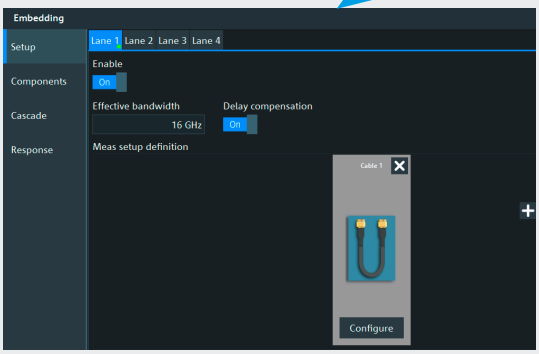
Benefit from preconfigured equalizer and embedding settings for many interface standards or customize your taps. Optimize the tap coefficients for FFE and DFE equalizers with automated training for your dedicated signal. Validate your setup with preview diagrams for transmission loss, step response or filter characteristics.

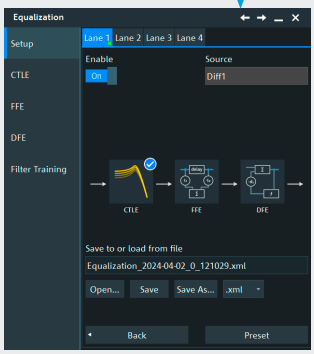


Define your signal lane:

- Transmitter equalizer (TxFFE): 1 precursor, 2 postcursors
- Embedding: up to 5 components
- Receiver equalizer
  1. CTLE with up to 6 zero and pole frequencies
  2. FFE with up to 40 taps
  3. DFE with up to 5 taps





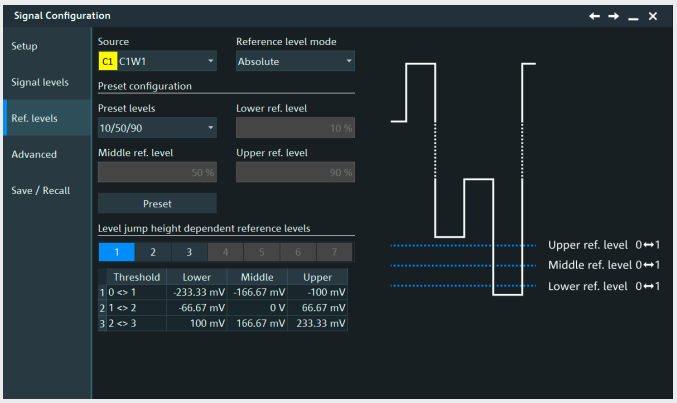


Most powerful PAM-N analysis

Up to PAM-8 order

The R&S®RTO6-K135 PAM-N analysis option enables measurements of signals up to the PAM-8 order. When the option is installed, R&S®RTO6 oscilloscopes can be used for additional PAM-N analysis together with the advanced eye, jitter and noise analysis options.

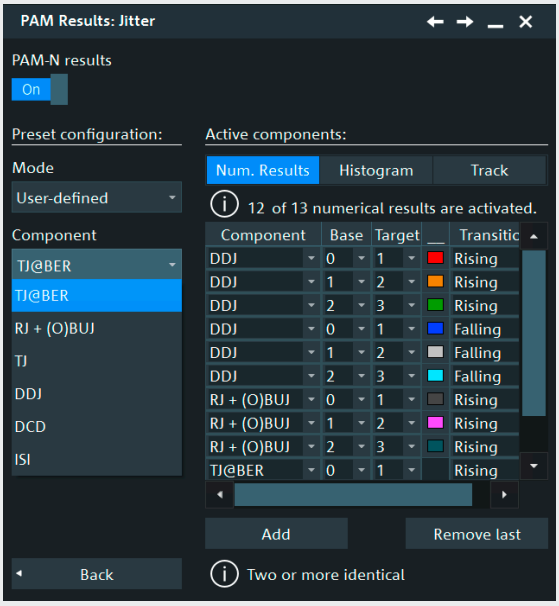
Select an interface standard via the easy signal configuration menu. For advanced customization, use full control to define signal levels and reference levels for all PAM levels and transitions.



Signal configurator: full control of signal and reference levels for PAM signals up to PAM-8

Jitter and noise decomposition at dedicated PAM levels

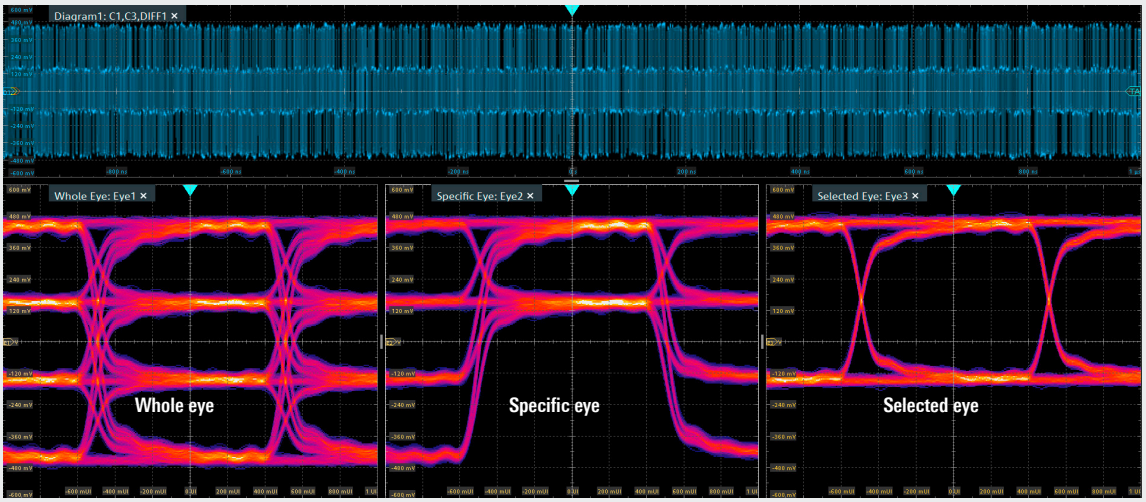
The R&S®RTO6-K135 PAM option enables additional jitter and noise analysis functions. The PAM enabled SW-CDR lets jitter and noise decomposition become available for various PAM signal components. Dedicated jitter and noise components can be selected for defined bases, in-depth analysis and to define target PAM levels.



PAM-N level specific result selection

Unique eye analysis

When the PAM option is activated, the PAM-N eye mask tests and eye measurements are available. Dedicated transitions and eye levels can be defined for the individual eye measurements. For the actual eye diagram, the user can choose between whole eye, specific eye and selected eye filter modes.



PAM-4 signal analysis: Eye diagram display with whole, selected and specific filter mode

JITTER AND NOISE ANALYSIS

Extensive debugging and analysis capabilities

- **Powerful basic jitter analysis**
- **Deep system insights with jitter and noise decomposition**
- **Clock data recovery for analyzing embedded clock signals in real time**
- **Serial pattern trigger**

Powerful basic jitter analysis functions

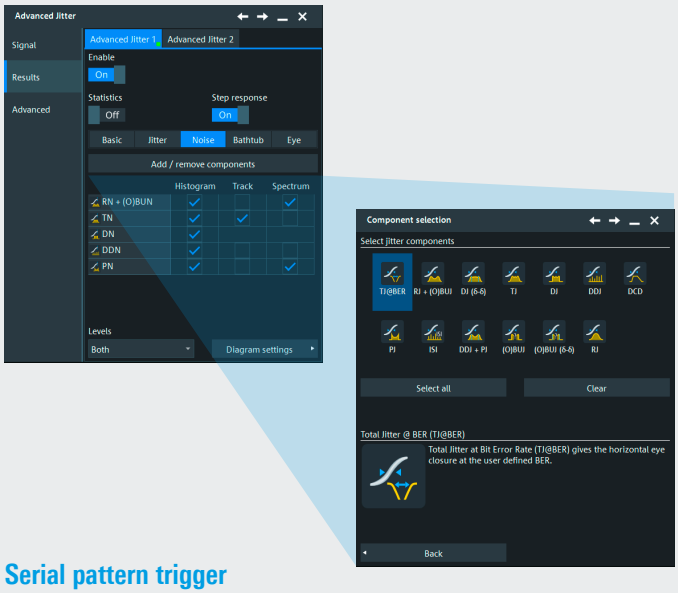
Get your jitter analysis of clock and data signals on track with automated jitter measurements for cycle-to-cycle jitter and time interval errors (TIE) and other tools like track, long-term trend and FFT. Frequency interference can be determined by applying FFT analysis to the cycle-to-cycle TIE jitter measurement track for example.

Jitter and noise measurement functions

R&S®RTO6-K134 option			
R&S®RTO6-K133 option		TJ (meas.)	TN (meas.)
R&S®RTO6-K12 option		TJ (at BER)	EH (at BER)
Standard functions	cycle-to-cycle jitter	RJ	RN RN + OBUN
Period	N-cycle jitter	RJ + OBUJ	DN
Frequency	cycle-to-cycle width	DJ	DDN
Setup	cycle-cycle duty	DJ (δδ)	ISIN
Setup/hold time	cycle	DDJ	LD
Setup/hold ratio	time interval error	ISI	PN
	data rate	DCD	DDN + PN
	unit interval	PJ	OBUN
	skew delay	DDJ + PJ	OBUN (δδ)
	skew phase	OBUJ	
		OBUJ (δδ)	

Deep system insights with jitter and noise decomposition

Gain more insights into your transmitter interface by decomposing jitter and noise into random (RJ/RN) and deterministic components, such as data dependent (DDJ/DDN) and periodic (PJ/PN) or other bounded uncorrelated components (OBUJ/OBUN). Calculating step responses that fully characterize the deterministic behavior of a transmission system enable ccurate measurement results even for relatively short signal sequences. In addition, synthetic eye diagrams and BER bathtub curves provide deeper insight into overall system behavior, individual jitter. Noise components can be displayed in histogram, track and spectrum view.

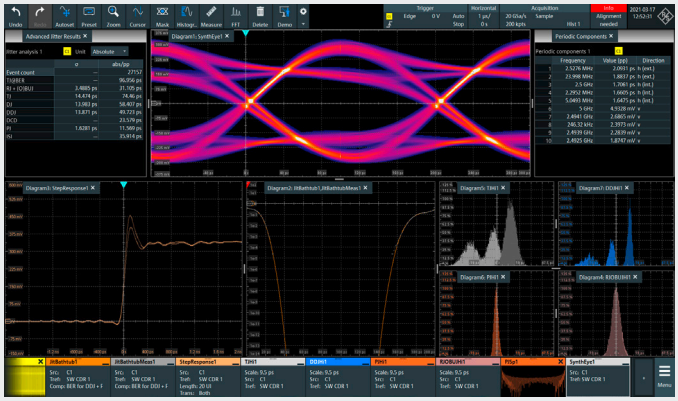


Serial pattern trigger

Combine the R&S®RTO6 with optional hardware-based clock data recovery or parallel clock signal to trigger on any serial interface data pattern of up to 16 byte with bit rates between 100 kbit/s and 2.5 Gbit/s. All analysis options are available.

Clock data recovery for analyzing embedded clock signals in real time

R&S®RTO6 oscilloscopes enable real-time clock data recovery of embedded clocks from serial interfaces thanks to their unique digital trigger architecture. As a result, eye and histogram measurements run continuously over a long period of time without any postprocessing. The hardware-based clock data recovery operates at the full acquisition rate without restricting oscilloscope functions. Furthermore, all automated jitter measurements can be performed on the recovered clock signal.



ADVANCED EYE ANALYSIS

Easy configuration

Up to four eye diagrams can be calculated based on the timestamps of the CDR. Traditional eye diagrams use software CDR functions in postprocessing which is time-consuming and requires a PLL settling time for each waveform acquisition.

The configurable CDR of the R&S®RTO6 supports data rates up to 6 Gbit/s for data eye analysis.

Advanced set of automatic eye measurements

Easy to use automated measurements are available for advanced eye analyses. Select from 15 measurements in the eye category and utilize all standard analysis functions such as statistics, track, histogram and trend displays.

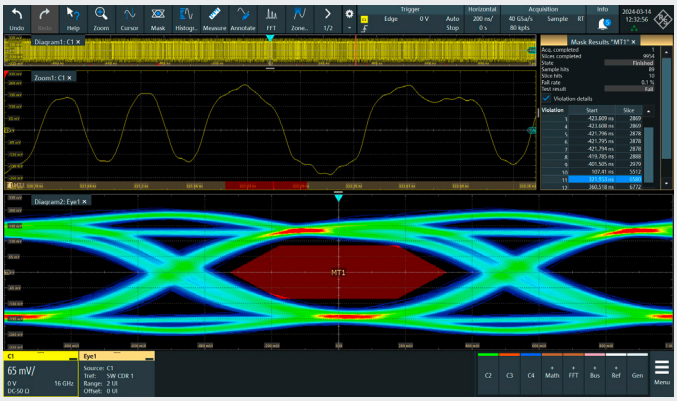
Select from an advanced set of automated Eye measurements

Comprehensive mask library

The standard histogram and the standard mask test function can be used for further analysis. Select from a comprehensive mask test library the right predefined mask for a dedicated standard such as USB, PCI Express and SATA.

Investigate mask test failures quickly

Use the eye stripe function of the advance eye option to investigate the details of mask test failures within the waveform. The eye stripe marks each of the mask test violations on the waveform. When zoom coupling is on, violations are directly in focus and users can navigate between mask violations easily.



The eye stripe function helps navigate between mask test failure and the position in the original waveform

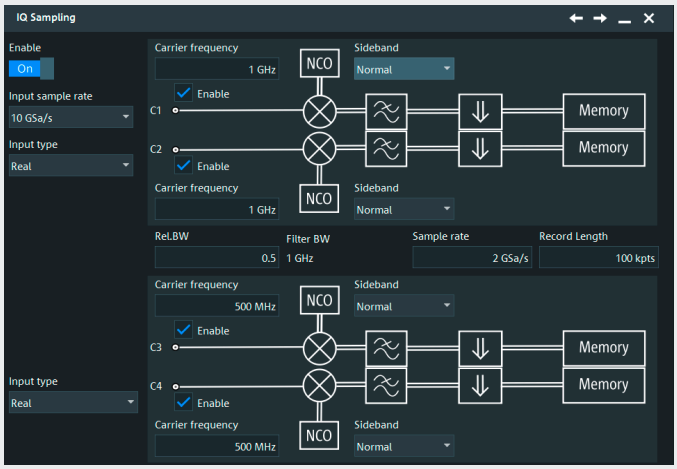
WIDEBAND RF AND SIGNAL ANALYSIS

Analyze I/Q data

- **Real-time conversion of modulated signals to I/Q data**
- **Precise wideband RF signal analysis**
- **Advanced signal analysis**

Real-time conversion of modulated signals to I/Q data

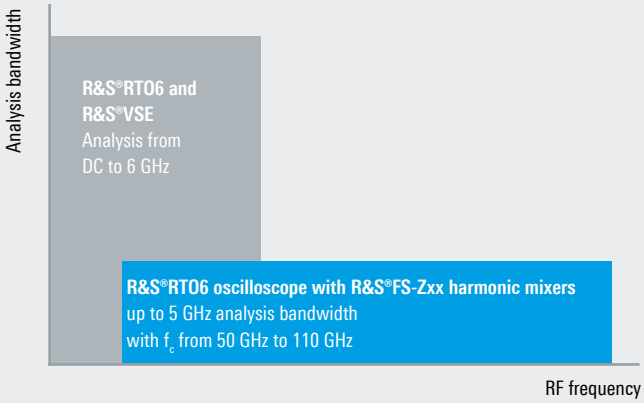
The I/Q interface of R&S®RTO6 oscilloscopes simplifies analysis of modulated signals by converting to I/Q data in real-time. The dedicated R&S®VSE vector signal explorer software or third-party tools such as MATLAB support further I/Q data processing.



Multichannel RF signal analysis

R&S®RTO6 oscilloscopes enable multichannel wideband RF measurements up to 6 GHz. When combined with R&S®FS-Zxx harmonic mixers, RF carrier frequencies between 50 GHz and 110 GHz are supported with an analysis bandwidth of 5 GHz. With outstanding RF characteristics of –159 dBm (1 Hz) and 112 dB SNR, the R&S®RTO6 is qualified to accurately analyze RF signals.

RF analysis



Advanced signal analysis

The R&S®RTO6 lets you analyze complex signals such as OFDM, radar and 5G MIMO signals with the help of R&S®VSE vector signal explorer software. The software offers a wide range of analysis tools for a large variety of modulated signals, ranging from pulsed and analog modulated signals to generic I/Q signals along with wireless and mobile communications standards such as LTE, 5G NR and WLAN.

Advanced RF analysis capabilities with the R&S®RTO6 oscilloscope

LOGIC ANALYSIS

Enhance your mixed-signal analysis capabilities

- **Mixed-signal option for logic analysis**
- **Additional 16 digital channels with no reduction of analog channels**
- **More signal details thanks to high time resolution over the entire memory depth**
- **Precise triggering on signal events**
- **Low test point loading from active probing**

Enhanced analysis capabilities with mixed-signal option

The unique R&S®RTO6 plug&play concept makes upgrading easy. The R&S®RTO6-B1 mixed-signal option (MSO) option adds 16 digital channels and is quick to install on site without opening the oscilloscope. Simply insert it into the slot on the rear panel and use all 16 digital channels of the MSO without losing any of the 4 analog input channels.

Straightforward display of digital signals

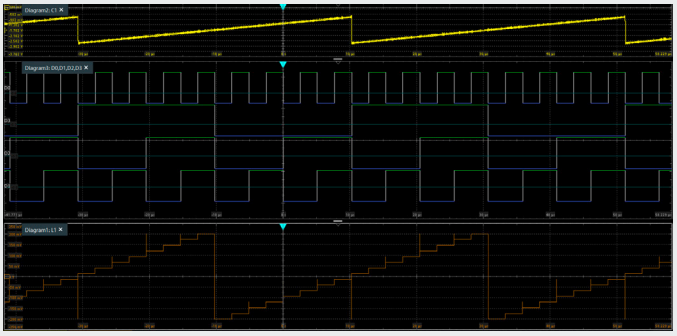
The R&S®RTO6-B1 option supports 16 digital channels and simultaneous decoding of up to four parallel buses. Each bus is represented by an icon on the edge of the screen. The R&S®SmartGrid function lets you simply drag&drop icons onto the screen. The icons clearly show the current status of all activated logic channels (high, low, toggle) regardless of other oscilloscope settings.

Specifications: R&S®RTO6-B1 MSO option

- 16 digital channels (2 logic probes with 8 channels each)
- Max. 400 MHz signal frequency
- Max. 5 Gsample/s per channel sampling rate
- Max. 200 Msample per channel acquisition memory
- High input impedance: 100 kΩ
- Low input capacitance: 4 pF

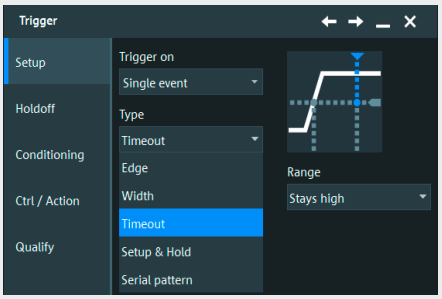
High time resolution over the entire memory depth

With a sampling rate of 5 Gsample/s, the R&S®RTO6-B1 mixed signal option (MSO) provides a maximum time resolution of 200 ps for all digital channels. This sampling rate is available over the entire memory depth of 200 Msample per channel. As a result, the MSO option can detect critical events such as narrow or widely separated glitches.



Precise triggering on signal events

The R&S®RTO6-B1 option offers numerous triggers for debugging and analysis, such as edge, width, pattern and serial pattern. These triggers can be combined with holdoff conditions. Choose either individual digital channels or bus signals as trigger sources. The digital channel resolution of 200 ps makes these channels a precise trigger source.



Analysis of parallel and serial protocols with digital channels

Use digital channels to decode parallel buses. They are displayed in a digital bus format or as an analog waveform. For clocked parallel buses, the decoded contents can also be displayed in a table. You can also use the digital channels of the R&S®RTO6-B1 option to decode serial interface protocols such as SPI and I²C.

SPECIALIZED SIGNAL ANALYSIS

Measurement options for in-depth measurements

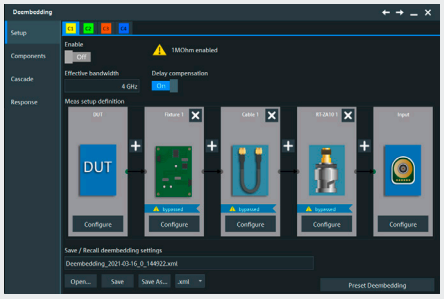
- **Realtime math for differential signals**
- **Deembedding for waveform correction**
- **Characterization and debugging of signal paths**
- **Differential pulse signal with configurable parameters**

Realtime math for differential signals

The R&S®RTO6 features a math module directly before the trigger system. It supports add, subtract and common mode calculation for two input channels. This enables fast analysis of differential signals, including triggering on the differential or common mode voltage. The math module also allows inversion of input signals.

Deembedding

Transmission losses caused by the signal path can be corrected by activating the deembedding option. A cascade of signal path blocks can be defined here. The individual blocks are described by S-parameters that can be derived from simulation or measured with a vector network analyzer. The deembedding software automatically calculates the correction filter for the overall system response.



Differential pulse source with configurable parameters

The R&S®RTO6-B7 pulse source provides a highly symmetrical differential pulse signal with a steep rise time of 22 ps. The key pulse source parameters are user adjustable. The output level ranges from –50 mV to –200 mV and can be set in 10 mV steps. The pulse repetition rate and the duty cycle are programmable in the range of 5 Hz to 250 MHz and 10% to 90%. The pulse source can be locked to the R&S®RTO6 reference clock or set to free running mode to avoid deterministic conditions for certain test applications.

Time-domain reflection/transmission (TDR/TDT)

The TDR/TDT option of R&S®RTO6 oscilloscopes combines the R&S®RTO6-B7 pulse source and the analog input channels to obtain a time-domain reflection (TDR) and transmission (TDT) analysis system. It supports the characterization and debugging of signal paths, including PCB traces, cables and connectors with single-ended measurements. A setup wizard guides the user through setup, calibration and analysis. The resulting waveforms are displayed as impedance or reflection coefficients versus time or distance. In addition, all oscilloscope analysis tools such as cursor and automated measurements can be used.

Differential pulse source	Value range
Analog bandwidth, rise time	> 16.5 GHz, 22 ps
Skew	< 0.5 ps
Output low level	–200 mV to –50 mV, 10 mV steps
Repetition rate	
Locked	5/10/20/50/100/200/500 Hz, 1/5/10/25/50/100/250 MHz
Free running	5/10/20/50/100/200/500 Hz, 1/5/10/25/50 MHz
Duty cycle	
Repetition rate < 5 MHz	10% to 90%, 10% steps
Repetition rate > 5 MHz	50% (const.)
Clock mode	locked, unlocked/free running

Application as DUT stimulus or deskewing

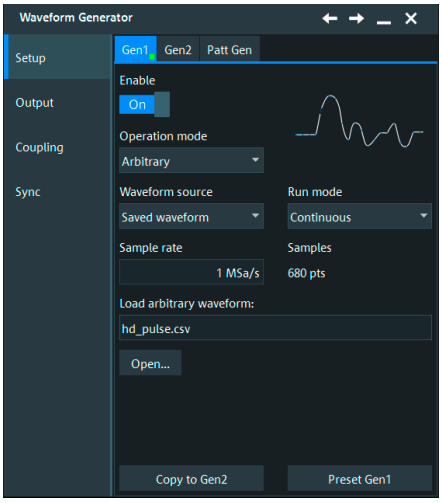
The R&S®RTO6-B7 can be easily set up as a stimulus for a DUT. For example, as a precise clock or as a pulse input with a fast rise time for testing receiver characteristics with TDR/TDT measurements. With an output skew of < 0.5 ps, the R&S®RTO6-B7 also provides an accurate source for deskewing measurement setups with multiple channels. Thanks to its differential nature, the R&S®RTO6-B7 is ideal for deskewing cables and probes for differential measurements.

COMPACT AND CONFIGURABLE
WAVEFORM GENERATION

- **Comes with a two-channel 100 MHz arbitrary waveform generator**
- **Single-ended and differential interface stimulation**
- **Test your device with native signals**

100 MHz arbitrary waveform generator

The R&S®RTO6 oscilloscopes are the first in this class to offer a fully integrated two-channel 100 MHz function generator, arbitrary waveform generator and eight-channel pattern generator. With 500 Msample/s and 14 bit resolution, the generator can be used for education purposes as well as design and R&D. The integrated generator saves space on the test bench and provides both standard and arbitrary stimulus to the DUT. The generator can be operated as a pattern, function or modulation generator. It also supports sweep mode and the playback of arbitrary waveform files.



Specifications: R&S®RTO6-B6 option

- Analog output: 2 channels
- Bandwidth: 100 MHz
- Sampling rate: 500 Msample/s
- Operating modes: Function generator (sine, square, ramp, DC, pulse, cardinal sine, cardiac, Gauss, Lorentz, exponential rise/fall)
- Modulation generator (AM, FM, FSK)
- Sweep generator
- Arbitrary waveform generator
- Pattern generator: 8 channels
- Memory: 40 Msample per channel
- Resolution: 14 bit

Single-ended and differential interface stimulation

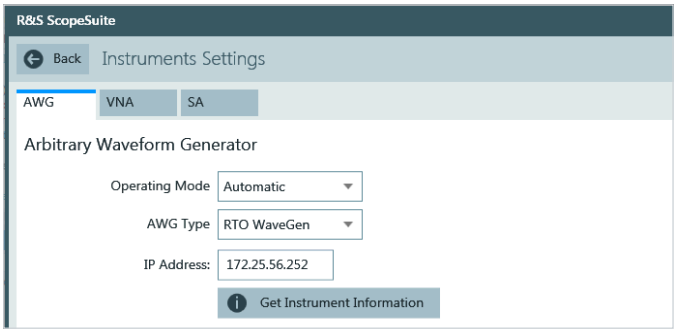
The generators can be coupled and offset from each other when testing differential devices. With the ability to offset amplitude and phase in coupled mode, you can simulate both ideal and non-ideal conditions. Differential devices, such as differential amplifiers or I/Q mixers, can be tested against amplitude impairments and phase imbalances.

Test your device with native signals

Testing your device with real-world signals opens up a new method for testing the limits of your design. The R&S®RTO6-B6 arbitrary waveform generator lets you play back waveforms captured on the oscilloscope. The captured waveforms can be manipulated by changing the amplitude and offset level or be superimposed with noise to evaluate a device against design criteria.

Fully automated compliance tests

Compliance tests can be fully automated with the R&S®RTO6-B6 arbitrary waveform generator, eliminating the need for an external signal source. R&S®ScopeSuite can control the waveform generator and provide the disturbing signal needed for Ethernet compliance testing, making the R&S®RTO6 the most compact compliance test solution on the market.



EXTENSIVE PROBE PORTFOLIO

THE RIGHT PROBE FOR THE BEST MEASUREMENT

- **Extensive probe range for all measurement tasks**
- **Micro button for convenient instrument control**
- **R&S®ProbeMeter: integrated voltmeter with 0.1 % measurement uncertainty for precise DC measurements**
- **Comprehensive accessories for maximum flexibility during contacting**

Extensive probe range for all measurement tasks

A complete portfolio of high-quality passive and active probes covers all measurement tasks. With an input impedance of 1 MΩ, the active probes put only a minimum load on a signal source operating point. The very large dynamic range, even at high frequencies, prevents signal distortion – for example: 60 V (V_{pp}) at 1 GHz for the active single-ended probes.

Multichannel power probes

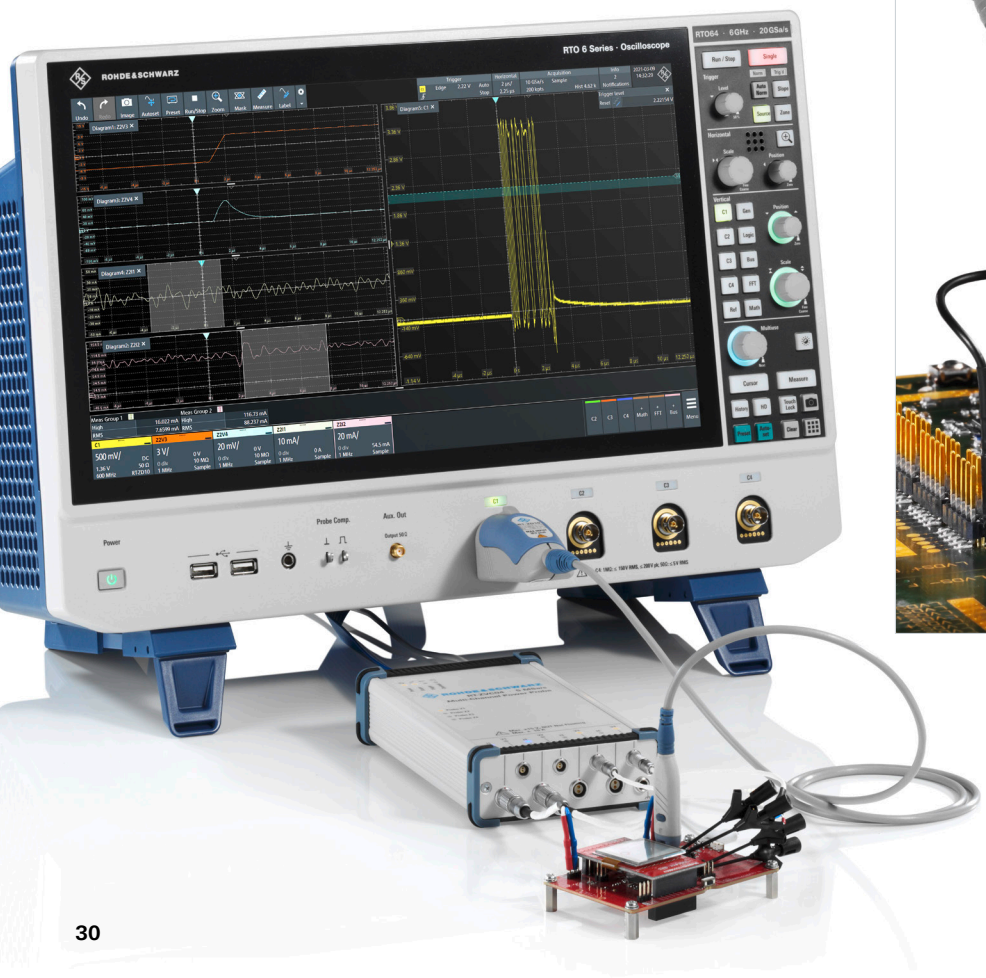
The R&S®RT-ZVC multichannel power probe offers up to four voltage and four current channels with 18 bit resolution for high dynamic range measurements. With up to two R&S®RT-ZVC probes supported by an R&S®RTO6 oscilloscope, you can analyze eight high dynamic range voltage and eight high dynamic range current signals synchronized with signals captured by the oscilloscope inputs.

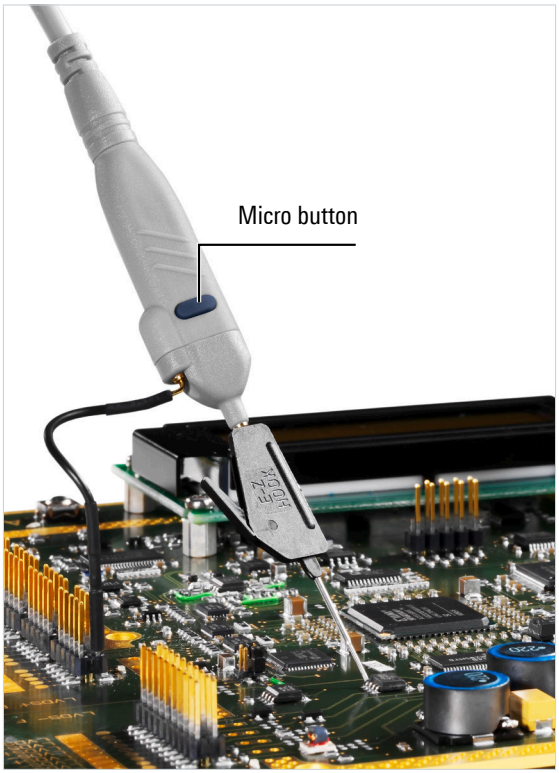
Micro button for convenient instrument control

The situation is all too familiar: you have carefully positioned the probe on the DUT and want to start measurements but no free hand. The micro button on Rohde & Schwarz active probes solves the problem. It is conveniently situated on the probe tip, and you can assign it different functions, such as run/stop, autoset and adjust offset.

R&S®ProbeMeter: integrated voltmeter for precise DC measurements

One connection lets you see the oscilloscope waveform and gives you access to a highly accurate voltmeter that shows the DC value regardless of other instrument settings.





Rohde & Schwarz has a comprehensive probe portfolio to meet every probing need.

▶ For more information, see product brochure "Probes and accessories for Rohde & Schwarz oscilloscopes" (PD 3606.8866.12)

Standard passive probes
(38 MHz to 500 MHz)
R&S®RT-ZP10, R&S®RT-ZP1x, R&S®RT-ZP03S

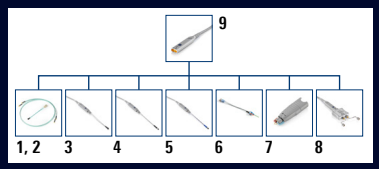
Passive probes come standard with every Rohde & Schwarz oscilloscope. They are low cost, general purpose probes for a broad range of applications.

Single ended broadband probes
(1 GHz to 6 GHz)
R&S®RT-ZS10E, R&S®RT-ZS10, R&S®RT-ZS20, R&S®RT-ZS30, R&S®RT-ZS60

A very high dynamic range and exceptionally low offset and gain errors combined with the right accessories make these probes ideal for Rohde & Schwarz oscilloscopes.

Differential broadband probes
(200 MHz to 4.5 GHz)
R&S®RT-ZD10, R&S®RT-ZD20, R&S®RT-ZD30, R&S®RT-ZD40

A flat frequency response and high input impedance with low input capacitance permit precise measurements on differential signals while maintaining a low load on the DUT. The CMMR for the entire probe bandwidth has high interference immunity. Special browser adapters allow flexible contacting with high signal fidelity.



1 R&S®RT-ZMA50; 2 R&S®RT-ZMA11; 3 R&S®RT-ZMA10; 4 R&S®RT-ZMA12; 5 R&S®RT-ZMA15; 6 R&S®RT-ZMA14; 7 R&S®RT-ZMA30; 8 R&S®RT-ZMA40; 9 R&S®RT-ZM

Modular broadband probes
(1.5 GHz to 16 GHz)
R&S®RT-ZM15, R&S®RT-ZM30, R&S®RT-ZM60, R&S®RT-ZM90, R&S®RT-ZM130, R&S®RT-ZM160

Current probing requirements need a technically sophisticated, yet easy-to-handle solution. The various probing solutions meet the demands for high probe bandwidths and dynamic range along with the need for low capacitive load.

Power rail probes
(2 GHz and 4 GHz)
R&S®RT-ZPR20, R&S®RT-ZPR40

High bandwidth, high sensitivity, very low noise and extra-large offset compensation make the R&S®RT-ZPR power rail probes an excellent tool for characterizing power rails. An integrated high accuracy DC voltmeter provides instantaneous DC voltage readout.

High voltage probes
(100 MHz to 400 MHz; ±750 V to ±6000 V)
R&S®RT-ZH03, R&S®RT-ZH10, R&S®RT-ZH11, R&S®RT-ZHD07, R&S®RT-ZHD15, R&S®RT-ZHD16, R&S®RT-ZHD60

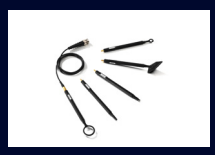
The Rohde & Schwarz portfolio of high voltage probes includes passive single-ended and active differential probes for voltages up to 6000 V (peak). Different models allow measurements up to CAT IV environments. Differential probes provide an exceptional common mode rejection ratio over a wide bandwidth.

Current probes
(20 kHz to 120 MHz; ±1 mA to ±2000 A)
R&S®RT-ZC02, R&S®RT-ZC03, R&S®RT-ZC05B, R&S®RT-ZC10, R&S®RT-ZC10B, R&S®RT-ZC15B, R&S®RT-ZC20, R&S®RT-ZC20B, R&S®RT-ZC30, R&S®RT-ZC31

Rohde & Schwarz current probes enable accurate, non-intrusive measurement of DC and AC currents. Different models are available to measure currents in the range of 1 mA to 2000 A with a bandwidth of up to 120 MHz. Current probes are available with Rohde & Schwarz probe interface or BNC with an external power supply.

Multichannel power probes
(1 MHz)
R&S®RT-ZVC02, R&S®RT-ZVC04

Multichannel power probe with 2 (or 4) voltage and 2 (or 4) current channels with 18 bit resolution. Up to two R&S®RT-ZVC probes are supported on an R&S®RTO6 oscilloscope. Capture eight voltage and eight current signals synchronized with the four oscilloscope channels.



EMC near-field probes
(30 MHz and 3 GHz)
R&S®HZ-15, R&S®HZ-17

Powerful E and H near-field probes for the frequency range from 30 MHz to 3 GHz with optional preamplifier expand the application range of the R&S®RTO6 oscilloscope series to include EMI debugging.

ACCESSORIES

Safe transport and easy rack mounting

An extensive selection of storage and transportation accessories means R&S®RTO6 oscilloscopes are always fully protected and easy to transport. The rackmount kit allows easy installation of the oscilloscope in integrated environments. Active, passive and logic probes can be stored in a special pouch on the rear panel of the R&S®RTO6 for easy accessibility.

Accessories	
Front cover	R&S®RTO6-Z1
Soft carrying case	R&S®RTO6-Z3
Transit case, with trolley function	R&S®RTO6-Z4
19" rackmount kit	R&S®ZZA-RTO6

FUTURE-PROOF YOUR INSTRUMENT

AN OSCILLSCOPE THAT EVOLVES WITH YOUR NEEDS

- **After-purchase bandwidth upgrades**
- **Regular firmware improvements**
- **Software options that support future technologies**
- **No hidden subscription fees**
- **Flexible hardware options**

Easy bandwidth upgrades for faster signals

Upgrading the bandwidth of an R&S®RTO6 oscilloscope to 1 GHz, 2 GHz or 3 GHz is possible without sending in the instrument to be serviced. Bandwidth upgrades to 4 GHz or 6 GHz benefit from a complete check of the instrument and calibration at a Rohde & Schwarz service center.

Firmware updates

Regular firmware updates consistently add new basic functions to R&S®RTO6 oscilloscopes. Download the latest firmware version at www.rohde-schwarz.com and use a USB storage device or LAN connection for installation. Your R&S®RTO6 oscilloscope is always up-to-date.

Application-specific software options

Unlocking comprehensive software options on R&S®RTO6 oscilloscopes enables the highly-specialized measurements required by state-of-the-art technologies. The constantly growing portfolio of new software options can cover your future test needs – even after purchasing the instrument:

- Triggering and decoding of serial protocols
- Automatic compliance tests on fast interfaces
- Detailed options for jitter analysis and power analysis
- Spectrum, power and signal analysis

On-site configuration of hardware options

The plug & play hardware concept enables R&S®RTO6 oscilloscopes to easily adapt to new requirements. Quick installation without opening the instrument is supported for all hardware options, such as digital channels for logic analysis or the waveform generator. This approach has many advantages:

- Straightforward extensibility for future tasks
- On-site installation of options in minutes
- No need to align or recalibrate after installing options

Exchangeable solid-state disk

No tools are needed to exchange the R&S®RTO6 solid-state drive, keeping confidential data protected at all times.

Rear view

SPECIFICATIONS OF BASE UNIT

Vertical system		
Input channels		4 channels
Input impedance		50 Ω ± 2.5% 50 Ω ± 1.5% (typ.), 1 MΩ ± 1% || 15 pF (meas.)
Analog bandwidth (–3 dB)	at 50 Ω input impedance	
	R&S®RTO6-B90 option	≥ 600 MHz
	R&S®RTO6-B91 option	≥ 1 GHz
	R&S®RTO6-B92 option	≥ 2 GHz
	R&S®RTO6-B93 option	≥ 3 GHz
	R&S®RTO6-B94 option	≥ 4 GHz
	R&S®RTO6-B96 option	≥ 6 GHz on 2 channels, ≥ 4 GHz on 4 channels
	at 1 MΩ input impedance	≥ 500 MHz (meas.)
Bandwidth limit filters		brick wall (noise optimized), Gaussian (step-response optimized)
Analog bandwidth limits	max. –1.5 dB, min. –4 dB	200 MHz, 20 MHz
Rise time/fall time	10% to 90% at 50 Ω, bandwidth limit Gaussian, except R&S®RTO6-B94 option brick wall (meas.)	
	R&S®RTO6-B90 option	528 ps
	R&S®RTO6-B91 option	319 ps
	R&S®RTO6-B92 option	188 ps
	R&S®RTO6-B93 option	135 ps
	R&S®RTO6-B94 option	104 ps
	R&S®RTO6-B96 option	77 ps
Input VSWR	input frequency	R&S®RTO6-B90, R&S®RTO6-B91, R&S®RTO6-B92, R&S®RTO6-B93, R&S®RTO6-B94 options
	≤ 2 GHz	1.25 (meas.)
	> 2 GHz	1.4 (meas.)
	input frequency	R&S®RTO6-B96 option
	≤ 2 GHz	1.25 (meas.)
	> 2 GHz to ≤ 4 GHz	1.6 (meas.)
	> 4 GHz	2.0 (meas.)
Vertical resolution		16 bit system architecture
Effective number of bits (ENOB) at 50 Ω, 50 mV/div, 10 MHz input signal with 90% full scale (meas.)		
Bandwidth		ENOB
50 MHz		9.4
100 MHz		9
200 MHz		8.6
300 MHz		8.2
500 MHz		8.1
1 GHz		7.7
2 GHz		7.1
4 GHz		6
6 GHz		6.1
DC gain accuracy	offset and position set to 0 V, after self-alignment	
	at 50 Ω, input sensitivity > 5 mV/div	±1.5%
	at 50 Ω, input sensitivity ≤ 5 mV/div	±2%
	at 1 MΩ	±2%
Input coupling	at 50 Ω	DC, GND
	at 1 MΩ	DC, AC (> 7 Hz), GND
Input sensitivity	at 50 Ω	1 mV/div to 1 V/div, entire analog bandwidth supported for all input sensitivities
	at 1 MΩ	1 mV/div to 10 V/div, entire analog bandwidth supported for all input sensitivities

Vertical system			
Maximum input voltage	at 50 Ω	5 V (RMS)	
	at 1 MΩ	150 V (RMS), 200 V (V_p), derates at 20 dB/decade to 5 V (RMS) above 250 kHz	
	at 1 MΩ with R&S®RT-ZP10 passive probe	400 V (RMS), 1650 V (V_p), 300 V (RMS) CAT II for derating and details see specifications R&S®RT-Zxx Standard Probes, PD 3607.3851.22	
Position range		±5 div	
Offset range at 50 Ω	input sensitivity		
	> 316 mV/div to ≤ 1 V/div	±10 V	
	> 100 mV/div to ≤ 316 mV/div	±3 V	
	1 mV/div to ≤ 100 mV/div	±1 V	
Offset range at 1 MΩ	input sensitivity		
	> 3.16 V/div to ≤ 10 V/div	±(115 V – input sensitivity × 5 div)	
	> 1 V/div to ≤ 3.16 V/div	±100 V	
	> 316 mV/div to ≤ 1 V/div	±(11.5 V – input sensitivity × 5 div)	
	> 100 mV/div to ≤ 316 mV/div	±10 V	
	> 31.6 mV/div to ≤ 100 mV/div	±(1.15 V – input sensitivity × 5 div)	
	1 mV/div to ≤ 31.6 mV/div	±1 V	
Offset accuracy		±(0.35 % × |net offset| + 2.5 mV + 0.1 div × input sensitivity) (net offset = offset – position × input sensitivity)	
DC measurement accuracy	after adequate suppression of measurement noise using high-resolution sampling mode, waveform averaging or a combination of both	±(DC gain accuracy × |reading – net offset| + offset accuracy)	
Channel-to-channel isolation (each channel at same input sensitivity)	input frequency within instrument bandwidth		
	≤ 2 GHz	> 60 dB	
	> 2 GHz to ≤ 4 GHz	> 50 dB	
	> 4 GHz to ≤ 6 GHz	> 40 dB	
RMS noise floor at instrument bandwidth at 50 Ω (typ.) (bandwidth limit brick wall)	input sensitivity	R&S®RTO6-B90 option	R&S®RTO6-B91 option
	1 mV/div	0.06 mV	0.09 mV
	2 mV/div	0.07 mV	0.09 mV
	5 mV/div	0.10 mV	0.12 mV
	10 mV/div	0.17 mV	0.20 mV
	20 mV/div	0.32 mV	0.37 mV
	50 mV/div	0.86 mV	0.93 mV
	100 mV/div	1.60 mV	1.79 mV
	200 mV/div	2.87 mV	3.53 mV
	500 mV/div	6.20 mV	8.76 mV
	1 V/div	10.9 mV	17.2 mV
	input sensitivity	R&S®RTO6-B92 option	R&S®RTO6-B93 option
	1 mV/div	0.13 mV	0.18 mV
	2 mV/div	0.13 mV	0.19 mV
	5 mV/div	0.16 mV	0.21 mV
	10 mV/div	0.26 mV	0.33 mV
	20 mV/div	0.49 mV	0.60 mV
	50 mV/div	1.18 mV	1.49 mV
	100 mV/div	2.37 mV	2.89 mV
	200 mV/div	4.68 mV	5.95 mV
	500 mV/div	12.1 mV	15.3 mV
	1 V/div	24.1 mV	29.7 mV

Vertical system

	input sensitivity		R&S®RTO6-B94 option	R&S®RTO6-B96 option
	1 mV/div		0.20 mV	0.30 mV
	2 mV/div		0.21 mV	0.30 mV
	5 mV/div		0.25 mV	0.31 mV
	10 mV/div		0.38 mV	0.43 mV
	20 mV/div		0.67 mV	0.73 mV
	50 mV/div		1.66 mV	1.73 mV
	100 mV/div		3.23 mV	3.26 mV
	200 mV/div		6.65 mV	6.68 mV
	500 mV/div		17.1 mV	17.3 mV
	1 V/div		34.2 mV	34.5 mV
RMS noise floor at instrument bandwidth at 1 MΩ (meas.)	input sensitivity			
	1 mV/div		0.13 mV	
	2 mV/div		0.13 mV	
	5 mV/div		0.17 mV	
	10 mV/div		0.26 mV	
	20 mV/div		0.47 mV	
	50 mV/div		1.15 mV	
	100 mV/div		2.30 mV	
	200 mV/div		4.70 mV	
	500 mV/div		11.5 mV	
	1 V/div		23.0 mV	
	2 V/div		46.0 mV	
	5 V/div		115 mV	
	10 V/div		230 mV	
RMS noise floor for HD mode at 50 Ω (meas.)	bandwidth	input sensitivity		
		1 mV/div	10 mV/div	100 mV/div
	10 MHz	10 µV	18 µV	150 µV
	100 MHz	31 µV	56 µV	470 µV
	500 MHz	63 µV	110 µV	960 µV
	1 GHz	92 µV	170 µV	1.41 mV
	2 GHz	140 µV	220 µV	1.78 mV

Horizontal system

Timebase range		selectable between 25 ps/div and 10 000 s/div, time per div settable to any value within range
Channel deskew		±100 ns
Reference position		0% to 100% of measurement display area
Trigger offset range	max.	+(memory depth/current sampling rate)
	min.	–10000 s
Modes		normal, roll
Channel-to-channel skew		< 100 ps (meas.)
Timebase accuracy	after delivery/calibration, at +23°C	±10 ppb
	during calibration interval	±100 ppb
	long-term stability (more than one year since calibration)	±(50 + 50 × years since calibration) ppb
Delta time accuracy	corresponds to time error between two edges on same acquisition and channel; signal amplitude greater than 5 divisions, measurement threshold set to 50%, vertical gain 10 mV/div or greater; rise time lower than four sample periods; waveform acquired in realtime mode	±(K/realtime sampling rate + timebase accuracy × |reading|) (peak) (meas.) where K = 0.15 (R&S®RTO6-B90 option) K = 0.18 (R&S®RTO6-B91 option) K = 0.25 (R&S®RTO6-B92 option) K = 0.37 (R&S®RTO6-B93 option) K = 0.43 (R&S®RTO6-B94 option) K = 0.55 (R&S®RTO6-B96 option)

Acquisition system		
Realtime sampling rate	R&S®RTO6-B90, R&S®RTO6-B91, R&S®RTO6-B92, R&S®RTO6-B93 options	max. 10 Gsample/s on each channel
	R&S®RTO6-B94, R&S®RTO6-B96 options	max. 10 Gsample/s on 4 channels, max. 20 Gsample/s on 2 channels
Realtime waveform acquisition rate	max.	> 1 000 000 waveforms/s
Memory depth [1]	standard	200 Mpoints on 4 channels, 400 Mpoints on 2 channels, 800 Mpoints on 1 channel
	R&S®RTO6-B104 option	400 Mpoints on 4 channels, 800 Mpoints on 2 channels (restriction: 400 Mpoints on 2 channels when channel 1 and 2 or channel 3 and 4 are turned on), 800 Mpoints on 1 channel
	R&S®RTO6-B110 option	1 Gpoints on 4 channels, 2 Gpoints on 2 channels (restriction: 1 Gpoints on 2 channels when channel 1 and 2 or channel 3 and 4 are turned on), 2 Gpoints on 1 channel
Realtime digital filters	selectable for the data acquisition and/or the trigger system	
	lowpass	cutoff frequency selectable from 100 kHz to analog bandwidth
Decimation modes	sample	first sample in decimation interval
	peak detect	largest and smallest sample in decimation interval
	high resolution	average value of samples in decimation interval
	root mean square	root of squared average of samples in decimation interval
Waveform arithmetic	off	no arithmetic
	envelope	envelope of acquired waveforms
	average	average of acquired waveforms, max. average depth depends on decimation mode [2]
	sample	max. 16 777 215
	high resolution	max. 65 535
	root mean square	max. 255
	reset condition	no reset (standard), reset by time, reset by number of processed waveforms
Waveform streams per channel		up to 3 with independent selection of decimation mode and waveform arithmetic
Sampling modes	realtime mode	max. sampling rate set by digitizer
	interpolated time	enhancement of sampling resolution by interpolation; max. equivalent sampling rate is 4 Tsample/s
Interpolation modes		linear, sin(x)/x, sample & hold
Ultra segmented mode	continuous recording of waveforms in acquisition memory without interruption due to visualization	
	max. realtime waveform acquisition rate	> 2 500 000 waveforms/s
	min. blind time between consecutive acquisitions	< 300 ns

Differential signals		
General description	Calculation of differential and common mode signals from p part and n part connected to separate input channels. The R&S®RTO64 digital trigger concept enables these signals to be used as a trigger input.	
Input channels		channel 1, channel 2, channel 3, channel 4
Differential signal	difference between two input channels	channel 1 and channel 2, channel 3 and channel 4
Common mode signal	sum of two input channels	channel 1 and channel 2, channel 3 and channel 4
Maximum number of outputs	differential signals	2
	common mode signals	2

[1] The maximum available memory depth depends on the bit depth of the acquired data and, therefore, on the settings of the acquisition system, such as decimation mode, waveform arithmetic, number of waveform streams or high definition mode.
[2] Waveform averaging is not compatible with peak detect decimation.

High definition mode		
General description	The high definition mode increases the numeric resolution of waveform signals with digital filtering to reduce noise. The signals with increased numeric resolution are used as a triggering input thanks to the R&S®RTO64 digital trigger concept.	
Numeric resolution	R&S®RTO6-B90, R&S®RTO6-B91, R&S®RTO6-B92, R&S®RTO6-B93, R&S®RTO6-B94	
	bandwidth	resolution
	10 kHz to 50 MHz	16 bit
	100 MHz	14 bit
	200 MHz	13 bit
	300 MHz	12 bit
	500 MHz	12 bit
	1 GHz	10 bit
	R&S®RTO6-B96 option (2 channels)	
	bandwidth	resolution
	10 kHz to 200 MHz	16 bit
	300 MHz	12 bit
	500 MHz	12 bit
	1 GHz	11 bit
	2 GHz	10 bit
	R&S®RTO6-B96 option (4 channels)	
	bandwidth	resolution
	10 kHz to 50 MHz	16 bit
	100 MHz	14 bit
	200 MHz	13 bit
	300 MHz	12 bit
	500 MHz	12 bit
	1 GHz	10 bit
Realtime sampling rate	R&S®RTO6-B90, R&S®RTO6-B91, R&S®RTO6-B92, R&S®RTO6-B93, R&S®RTO6-B94, R&S®RTO6-B96 options (4 channels)	max. 5 Gsample/s on each channel
	R&S®RTO6-B94, R&S®RTO6-B96 options (2 channels)	max. 10 Gsample/s on each channel
Input sensitivity		input sensitivity range extends down to 500 µV/div; 500 µV/div is a magnification of 1 mV/div setting.

Trigger system		
Sources		channel 1, channel 2, channel 3, channel 4, inverted channels, external trigger, differential, common mode
Sensitivity		10^{-4} div, from DC to instrument bandwidth for all vertical scales
Trigger jitter	full-scale sine wave of frequency set to –3 dB bandwidth	< 1 ps (RMS) (meas.)
Coupling mode	standard	same as selected channel
	lowpass filter	cutoff frequency selectable from 100 kHz to 50 % of analog bandwidth
Sweep mode		auto, normal, single, n single
Event rate	max.	one event for every 400 ps time interval
Trigger level	range	±5 div from center of screen
Trigger hysteresis	modes	auto (standard) or manual
	sensitivity	10^{-4} div, from DC to instrument bandwidth for all vertical scales
Holdoff range	time	100 ns to 10 s, fixed and random
	events	1 event to 2 000 000 000 events

Trigger system		
Main trigger modes		
Edge	triggers on specified slope (positive, negative or either) and level	
Glitch	triggers on glitches of positive, negative or either polarity that are shorter or longer than specified width	
	glitch width	100 ps to 1000 s
		50 ps to 1000 s (R&S®RTO6-B94, R&S®RTO6-B96 options)
Width	triggers on positive or negative pulse of specified width; width can be shorter, longer, inside or outside the interval	
	pulse width	100 ps to 1000 s
		50 ps to 1000 s (R&S®RTO6-B94, R&S®RTO6-B96 options)
Runt	triggers on pulse of positive, negative or either polarity that crosses one threshold but fails to cross a second threshold before recrossing the first one; runt pulse width can be arbitrary, shorter, longer, inside or outside the interval	
	runt pulse width	100 ps to 1000 s
		50 ps to 1000 s (R&S®RTO6-B94, R&S®RTO6-B96 options)
Window	triggers when signal enters or exits a specified voltage range; triggers also when signal stays inside or outside the voltage range for a specified period of time	
Timeout	triggers when signal stays high, low or unchanged for a specified period of time	
	timeout	100 ps to 1000 s
		50 ps to 1000 s (R&S®RTO6-B94, R&S®RTO6-B96 options)
Interval	triggers when time between two consecutive edges of same slope (positive or negative) is shorter, longer, inside or outside a specified range	
	interval time	100 ps to 1000 s
		50 ps to 1000 s (R&S®RTO6-B94, R&S®RTO6-B96 options)
Slew rate	triggers when the time required by a signal edge to toggle between user-defined upper and lower voltage levels is shorter, longer, inside or outside the interval; edge slope may be positive, negative or either	
	toggle time	100 ps to 1000 s
		50 ps to 1000 s (R&S®RTO6-B94, R&S®RTO6-B96 options)
Data2clock	triggers on setup time and hold time violations between clock and data present on any two input channels; users can specify monitored time interval ranging from –100 ns to 100 ns around a clock edge and must be at least 100 ps wide	
Pattern	triggers when a logical combination (and, nand, or, nor) of the input channels stays true for a period of time shorter, longer, inside or outside a specified range	
State	triggers when a logical combination (and, nand, or, nor) of the input channels stays true at a slope (positive, negative or either) in one selected channel	
Serial pattern	triggers on serial data pattern up to 128 bit clocked by one input channel; pattern bits may be high (H), low (L) or don't care (X); clock edge slope may be positive, negative or either; hardware CDR selectable as clock source (requires R&S®RTO6-K13 option)	
	max. data rate	< 2.50 Gbit/s
		< 5 Gbit/s (R&S®RTO6-B94, R&S®RTO6-B96 options)
TV/video	triggers on baseband analog progressive and interlaced video signals including NTSC, PAL, PAL-M, SECAM, EDTV and HDTV broadcast standards as well as custom bi-level and tri-level sync video standards	
	trigger modes	all fields, odd fields, even fields, all lines, line number

Trigger system

Advanced trigger modes		
Zone trigger	triggers on user-defined zones drawn on the display	
	source	acquired waveforms (input channels), math waveforms
	number of zones	up to 8
	zone shapes	rectangles, polygones
	zone types	must intersect, must not intersect
	combination of zones	logical combination of zones of multiple sources using Boolean expressions
	trigger compatibility	compatible with the edge, glitch, width, runt, window, timeout, interval, slew rate, data2clock, pattern, state, serial pattern, trigger qualification, and sequence trigger modes
Trigger qualification	trigger events may be qualified by a logical combination of unused channels	
	qualifiable events	edge, glitch, width, runt, window, timeout, interval
Sequence trigger (A/B/R trigger)	triggers on B event after occurrence of A event; delay condition after A event specified either as time interval or number of B events; an optional R event resets the trigger sequence to A	
	A event	any trigger mode
	B event	edge, glitch, width, runt, window, timeout, interval, slew rate
	R event	edge, glitch, width, runt, window, timeout, interval, slew rate
Serial bus trigger	optional	see dedicated triggering and decoding options
NFC trigger		with R&S®RTO6-K11 option
CDR trigger	triggers on clock signal recovered from the trigger source signal; phase of the trigger instant user-selectable as fraction of bit period; requires R&S®RTO6-K13 option	
	CDR configuration parameters	PLL order (first or second), nominal bit rate, loop bandwidth, relative bandwidth, damping factor, unit interval offset
	CDR bit rate range	
	R&S®RTO6-B90, R&S®RTO6-B91, R&S®RTO6-B92, R&S®RTO6-B93 options	200 kbit/s to 2.5 Gbit/s
	R&S®RTO6-B94, R&S®RTO6-B96 options	200 kbit/s to 2.5 Gbit/s standard, 400 kbit/s to 5.0 Gbit/s when operating at 20 Gsample/s realtime sampling rate[3]
External trigger input	input impedance	50 Ω (nom.) or 1 MΩ (nom.) || 20 pF (meas.)
	max. input voltage at 50 Ω	5.5 V (peak)
	max. input voltage at 1 MΩ	30 V (RMS) derates at 20 dB/decade to 5 V (RMS) above 25 MHz
	trigger level	±5 V
	sensitivity	
	input frequency ≤ 100 MHz	300 mV (V_{pp})
	100 MHz < input frequency ≤ 500 MHz	600 mV (V_{pp})
	input coupling	AC, DC (50 Ω and 1 MΩ), GND, HF reject (attenuates > 50 kHz or > 50 MHz, user-selectable), LF reject (attenuates < 5 kHz or < 50 kHz, user-selectable)
	trigger modes	edge (rise or fall)

[3] The frontends of the R&S®RTO6-B94 and the R&S®RTO6-B96 sample at 20 Gsample/s when at most one channel of each pair {channel 1, channel 2} and {channel 3, channel 4} is active; and the user-selected sampling resolution in realtime sampling mode or interpolated time sampling mode is 50 ps or smaller.

Trigger system		
Trigger out	functionality	a pulse is generated for every acquisition trigger event
	output voltage	0 V to 5 V at high impedance; 0 V to 2.5 V at 50 Ω
	pulse width	selectable between 50 ns and 60 ms
	pulse polarity	low active or high active
	output delay	depends on trigger settings
	jitter	±600 ps (meas.)

RF characteristics [4]		
Sensitivity/noise density	at 1.001 GHz (measurement of the power spectral density at 1.001 GHz at input sensitivity 1 mV/div, corresponding to –36 dBm input range of the oscilloscope, using the FFT with center frequency 1.001 GHz, span 500 kHz, RBW 3 kHz)	–159 dBm (1 Hz) (meas.)
	at 100 kHz (measurement of the power spectral density at 100 kHz at input sensitivity 1 mV/div, corresponding to –36 dBm input range of the oscilloscope, using the FFT with center frequency 100 kHz, span 20 kHz, RBW 200 Hz)	–156 dBm (1 Hz) (meas.)
Noise figure	at 1.001 GHz (calculated based on the noise density above)	15 dB (meas.)
	at 100 kHz (calculated based on the noise density above)	18 dB (meas.)
Signal-to-noise ratio	measured for an input carrier with frequency 1 GHz and level 0 dBm at input sensitivity 70 mV/div, corresponding to 0 dBm input range of the oscilloscope, using the FFT with center frequency 1 GHz, span 100 MHz, RBW 400 Hz at +20 MHz from the center frequency	112 dB (meas.)
Absolute amplitude accuracy	0 Hz to 5 GHz	±1 dB (meas.)
Spurious-free dynamic range	measured for an input carrier with frequency 950 MHz and level 0 dBm at input sensitivity 70 mV/div, corresponding to 0 dBm input range of the oscilloscope, using the FFT with center frequency 2 GHz, span 4 GHz, RBW 100 kHz	68 dBc (meas.)
Second harmonic distortion	measured for an input carrier with frequency 950 MHz and level 0 dBm at input sensitivity 70 mV/div, corresponding to 0 dBm input range of the oscilloscope, using the FFT with center frequency 950 MHz, span 4 GHz, RBW 100 kHz	–49 dBc (meas.)
Third harmonic distortion	measured for an input carrier with frequency 950 MHz and level 0 dBm at input sensitivity 70 mV/div, corresponding to 0 dBm input range of the oscilloscope, using the FFT with center frequency 950 MHz, span 4 GHz, RBW 100 kHz	–44 dBc (meas.)

Waveform measurements		
General features	measurement panels	up to 8 measurement panels; each panel may contain any number of automatic measurements of the same category
	gate	delimits the display region evaluated for automatic measurements
	reference levels	user-configurable vertical levels define support structures for automatic measurements
	statistics	displays maximum, minimum, mean, standard deviation, RMS and measurement count for each automatic measurement
	track	measurement results displayed as continuous trace that is time-correlated to the measurement source
	long-term analysis	history of selected measurements as trace against count index

[4] The RF characteristics are measured for the R&S®RTO6-B96 option with 6 GHz bandwidth.

Waveform measurements		
	histogram	available for the main measurement of each measurement panel; automatic or manual selection of bin number and scale; counters for measurements under, within and over the histogram range
	limit check	measurements tested against user-defined margins and limits; pass or fail conditions may launch automatic response: acquisition stop, beep, print and save waveform
Measurement category	amplitude and time	amplitude, high, low, maximum, minimum, peak-to-peak, mean, RMS, sigma, overshoot, area, rise time, fall time, positive width, negative width, period, frequency, duty cycle, delay, phase, burst width, pulse count, positive switching, negative switching, cycle area, cycle mean, cycle RMS, cycle sigma, setup/hold time, setup/hold ratio, pulse train, slew rate rising, slew rate falling, DC voltmeter (requires Rohde&Schwarz active probe with R&S®ProbeMeter function)
	eye diagram	extinction ratio, eye height, eye width, eye top, eye base, Q factor, S/N ratio, duty cycle distortion, eye rise time, eye fall time, eye bit rate, eye amplitude, jitter (peak-to-peak, 6-sigma, RMS)
	spectrum	channel power, bandwidth, occupied bandwidth, harmonic search, total harmonic distortion THD in dB and % using power values, total harmonic distortion variants THD_a, THD_u and THD_r using voltage, overall voltage and overall voltage root means square, peak list (THD_a, THD_u and THD_r require R&S®RTO6-K37 option)
	jitter	cycle-to-cycle jitter, N-cycle jitter, cycle-to-cycle width, cycle-to-cycle duty cycle, time-interval error, data rate, unit interval, skew delay, skew phase; requires R&S®RTO6-K12 option
Cursors	setup	up to 4 cursor sets on screen, each set consisting of two horizontal and two vertical cursors
	target	acquired waveforms (input channels), math waveforms, reference waveforms, track waveforms, XY diagrams
	operating mode	vertical measurements, horizontal measurements or both; vertical cursors either set manually or locked to waveform
Histogram	source	acquired waveform (input channels), math waveform, reference waveform
	mode	vertical (for timing statistics), horizontal (for amplitude statistics)
	automatic measurements	waveform count, waveform samples, histogram samples, histogram peak, peak value, maximum, minimum, median, range, mean, sigma, mean ± 1, 2 and 3 sigma, marker ± probability

Mask testing		
Test definition	number of masks	up to 8 simultaneously
	source	acquired waveforms (input channels), math waveforms
	fail condition	sample hit or waveform hit
	fail tolerance	minimum number of fail events for test fail in range from 0 to 4 000 000 000
	test rate	up to 600 000 waveforms/s
	action on error	acquisition stop, beep, print and save waveform
	save/load to file	test and mask settings (.xml format)

Mask testing		
Mask definition with segments	number of independent segments	up to 8
	segment definition	array of points and connecting rule (upper, lower, inner) define segment region
	segment input	point and click on touchscreen, editable list
Mask definition with tolerance tube	input signal	acquired waveform
	definition of tolerance tube	horizontal width, vertical width, vertical stretch, vertical position
Mask definition with eye mask assistant (requires R&S®RTO6-K12 option)	primary mask shape	
	type	diamond, square, hexagon, octagon
	dimensions	main and secondary height, main and secondary width, depending on selected shape
	position	vertical offset, horizontal offset
	secondary mask shapes	
	locations	any combination of left, right, top, bottom
	position	horizontal and vertical offset with respect to center of primary mask shape
Result statistics	category	completed acquisitions, remaining acquisitions, state, sample hits, mask hits, fail rate, test result (pass or fail)
Visualization options	waveform style	vectors, dots
	violation highlighting	hits (on/off), highlight persistence (50 ms to 50 s or infinite), waveform color (default: red)
	mask colors	configurable colors for mask without violation (default: translucent gray), mask with violation (default: translucent red), mask with contact (default: translucent pale red)

Waveform math		
General features	number of math waveforms	up to 8
	number of reference waveforms	up to 4
	waveform arithmetic	user-selectable average or envelope of consecutive waveforms
Algebraic expressions	user may define complex mathematical expressions involving waveforms and measurement results	
	math functions	add, subtract, multiply, divide, absolute value, square, square root, integrate, differentiate, exp, $\log_{10}$, $\log_e$, $\log_2$, rescale, sin, cos, tan, arcsin, arccos, arctan, sinh, cosh, tanh, autocorrelation, crosscorrelation
	logical operators	not, and, nand, or, nor, xor, nxor
	relational operators	Boolean result of =, ≠, >, <, ≤, ≥
	frequency domain	spectral magnitude and phase, real and imaginary spectra, group delay
	digital filter	lowpass, highpass
	special functions	CDR transform; requires R&S®RTO6-K12 option
Optimized math	operators	add, subtract, multiply, invert, absolute value, differentiate, $\log_{10}$, $\log_e$, $\log_2$, rescale, FIR, FFT magnitude
Spectrum analysis	FFT magnitude spectrum	
	setup parameters	center frequency, frequency span, frame overlap, frame window (rectangular, Hamming, Hann, Blackman, Gaussian, Flattop, Kaiser Bessel), user-selectable spectrum averaging, RMS, envelope, max. hold and min. hold (max. hold and min. hold require R&S®RTO6-K37 option)
	max. realtime waveform acquisition rate	> 1000 waveforms/s

Search and mark function		
General description	scans acquired waveforms for occurrence of a user-defined set of events and highlights each occurrence	
Basic setup	source	all physical input channels, math waveforms, reference waveforms
	search panels	up to 8, where each panel may manage multiple event searches
	search mode	manually triggered or continuous
	search conditions	
	supported events	edge, glitch, width, runt, window, timeout, interval, slew rate, data2clock, state
	event configuration	identical to corresponding trigger event
	event selection	single or multiple events on same source
Search oscilloscope	mode	current waveform, gated time interval
Result visualization	table	
	sort mode	horizontal position or vertical value
	max. result count	specifies max. table size
	zoom window	centered on highlighted event

Display characteristics	
Diagram types	Yt, XY, spectrum, long-term measurement, spectrogram (spectrogram requires R&S®RTO6-K37 option)
Display interface configuration	display area can be split up into separate diagram areas by dragging and dropping signal icons; each diagram area can hold any number of signals; diagram areas may be stacked on top of each other and later accessed via the dynamic tab menu
Signal icon	each active waveform is represented by a separate signal icon on the signal bar; the signal icon displays individual vertical and acquisition settings; a waveform can be minimized to signal icon to appears as a realtime preview in miniature; measurement results may also be minimized to a signal icon
Toolbar	quick access to 28 important tools; directly set most common parameters in a simple menu and access to more detailed parameters in main menu; user-defined selection of tools in toolbar
Upper menu	displays trigger, horizontal and acquisition settings; quick access to settings
Main menu	provides access to all instruments settings in compact menu
Axis label	X-axis ticks and Y-axis ticks labeled with tick value and physical unit
Diagram label	diagrams may be individually labeled with a descriptive user-defined name
Diagram layout	grid, crosshair, axis labels and diagram label may be switched on and off separately
Persistence	50 ms to 50 s, or infinite
Zoom	user-defined zoom window provides vertical and horizontal zoom; each diagram area supports multiple zoom windows; touchscreen interface simplifies resize and drag operations on zoom window
Signal colors	predefined or user-defined color tables for persistence display

Input and output		
Front		
Channel inputs		BNC-compatible, for details see vertical system
	probe interface	auto-detection of passive probes, Rohde&Schwarz active probe interface
Auxiliary output		SMA connector, for future use
Probe compensation output	signal shape	rectangle, V_{low} = 0 V, V_{high} = 1 V amplitude 1 V (V_{pp}) ± 5%
	frequency	1 kHz ± 1%
	impedance	nom. 50 Ω
Ground jack		connected to ground
USB interface		2 ports, type A plug, version 2.0

Input and output		
Rear		
External trigger input		BNC, for details see trigger system
Trigger out		BNC, for details see trigger system
USB interface		2 ports, type A plug and 1 port, type B plug, version 3.1 Gen 1
LAN interface		RJ-45 connector, supports 10/100/1000BASE-T
External monitor interface		HDMI 2.0 and DisplayPort++ 1.3, output of oscilloscope display or extended desktop display
GPIB interface		see R&S®RTO6-B10 option
Reference input	connector	BNC female
	impedance	50 Ω (nom.)
	input frequency range	1 MHz to 20 MHz, in 1 MHz steps
	sensitivity	≥ 0 dBm into 50 Ω, ≥ 8 dBm at 1 MHz
Reference output	connector	BNC female
	impedance	50 Ω (nom.)
	output signal with internal reference	10 MHz (specified in timebase accuracy), 7 dBm (nom.)
	output signal with external reference	none
Security slot		for standard Kensington style lock

General data		
Display	type	15.6" LC TFT color display with capacitive touchscreen
	resolution	1920 × 1080 pixel (full HD)
Temperature		
Temperature loading	operating temperature range	0 °C to +45 °C
	storage temperature range	–40 °C to +70 °C
Temperature loading		in line with MIL-PRF-28800F section 4.5.5.1.1.1 class 3 tailored to +45 °C for operation
Climatic loading		+25 °C/+40 °C at 85 % relative humidity cyclic, in line with IEC 60068-2-30
		+30 °C/+40 °C/+45 °C at 95/75/45 %, in line with MIL-PRF-28800F section 4.5.5.1.1.2 class 3 tailored to +45 °C for operation
Altitude		
Operating		up to 3000 m above sea level
Nonoperating		up to 4600 m above sea level
Mechanical resistance		
Vibration	sinusoidal	5 Hz to 150 Hz, max. 1.8 g at 55 Hz; 0.5 g from 55 Hz to 150 Hz, in line with EN 60068-2-6
		5 Hz to 55 Hz, in line with MIL-PRF-28800F section 4.5.5.3.2 class 3
	random	8 Hz to 500 Hz, acceleration 1.2 g (RMS), in line with EN 60068-2-64
		5 Hz to 500 Hz, acceleration 2.058 g (RMS), in line with MIL-PRF-28800F section 4.5.5.3.1 class 3
Shock		40 g shock spectrum, in line with MIL-STD-810G, method no. 516.6, procedure I
		30 g functional shock, halfsine, duration 11 ms, in line with MIL-PRF-28800F section 4.5.5.4.1

General data		
EMC		
RF emission		in line with CISPR 11/EN 55011 group 1 class A (for a shielded test setup); instrument complies with EN 55011, EN 61326-1 and EN 61326-2-1 class A emission requirements and is suitable for use in industrial environments
Immunity		in line with IEC/EN 61326-1 table 2, immunity test requirements for industrial environment[5)]
Certifications		VDE, $_{c}$CSA$_{US}$, KC
Calibration interval		1 year
Power supply		
AC supply		100 V to 240 V at 50 Hz to 60 Hz and 400 Hz, max. 5.5 A to 2.3 A, in line with MIL-PRF 28800F section 3.5
Power consumption		max. 450 W
Safety		in line with IEC 61010-1, EN 61010-1, CAN/CSA-C22.2 No. 61010-1, UL 61010-1
Mechanical data		
Dimensions	W × H × D	450 mm × 315 mm × 204 mm (17.72 in × 12.40 in × 8.03 in)
Weight	without options, nominal	10.7 kg (23.59 lb)

[5)] Test criterion is displayed noise level within ±1 div for input sensitivity of 5 mV/div.

ORDERING INFORMATION

Designation	Type	Order No.		
Step 1: base instrument				
4 channel oscilloscope	R&S®RTO64	1802.0001.04		
Step 2: choose one bandwidth option (mandatory)				
600 MHz	R&S®RTO6-B90	1802.0182.02		
1 GHz	R&S®RTO6-B91	1802.0199.02		
2 GHz	R&S®RTO6-B92	1802.0201.02		
3 GHz	R&S®RTO6-B93	1802.0218.02		
4 GHz	R&S®RTO6-B94	1802.0224.02		
6 GHz	R&S®RTO6-B96	1802.0230.02		
Step 3: choose your hardware options				
Mixed-signal option 400 MHz, 16 digital channels	R&S®RTO6-B1	1801.6741.02		
Digital extension port (required for R&S®RT-ZVC)	R&S®RTO6-B1E	1801.6735.02		
Arbitrary waveform generator	R&S®RTO6-B6	1801.6758.02		
Memory upgrade, 400 Mpoints per channel	R&S®RTO6-B104	1801.6793.02		
Memory upgrade, 1 Gpoints per channel	R&S®RTO6-B110	1801.6806.04		
Differential pulse source 16 GHz	R&S®RTO6-B7	1801.6764.02		
GPIB interface	R&S®RTO6-B10	1801.6770.02		
Replacement solid state disk	R&S®RTO6-B19	1801.6787.03		
Step 4: choose serial trigger and decode software options			**Included protocols**	
Bus analysis	R&S®RTO6-K500	1801.6864.02		
Low speed serial buses	R&S®RTO6-K510	1801.7019.02	I²C/SPI/RS-232/UART/I²S/LJ/RJ/TDM/Manchester/NRZ	
Automotive protocols	R&S®RTO6-K520	1801.7025.02	CAN/CAN XL/LIN incl. CAN-dbc file import/CAN FD, FlexRay incl. Fibex file import/SENT/CXPI	
Aerospace protocols	R&S®RTO6-K530	1801.7031.02	MIL-STD-1553/ARINC 429/SpaceWire	
Ethernet protocols	R&S®RTO6-K540	1801.7048.02	10BASE-T/100BASE-TX/MDIO	
MIPI low speed	R&S®RTO6-K550	1801.7054.02	MIPI RFFE, I³C	
Automotive Ethernet	R&S®RTO6-K560	1801.7060.02	IEEE 10BASE-T1S/100BASE-T1/1000BASE-T1	
USB protocols	R&S®RTO6-K570	1801.7077.02	USB 1.0/1.1/USB 2.0/HSIC/USB 3.1 Gen 1, USB Power Delivery (USB-PD)/USB SSIC	
MIPI M-PHY, D-PHY	R&S®RTO6-K580	1801.7083.02	MIPI D-PHY/M-PHY/UniPro/Decoding for DSI und CSI-2	
PCI Express	R&S®RTO6-K590	1801.7090.02	8b10b (up to 6.25 Gbit/s)/PCI Express Revision 1.x/2.x	
Trigger and decode bundle	R&S®RTO6-TDBDL	1801.7725.02	R&S®RTO6-K500/-K510/-K520/-K530/-K540/-K550/-K560/-K570/-K580/-K590	
Step 5: choose general analysis software options				
I/Q software interface	R&S®RTO6-K11	1801.6812.02		
Jitter analysis	R&S®RTO6-K12	1801.6829.02		
Clock data recovery	R&S®RTO6-K13	1801.6835.02		
Power analysis	R&S®RTO6-K31	1801.6858.02		
Spectrum analysis	R&S®RTO6-K37	1801.6870.02		
User-defined math with Python	R&S®RTO6-K39	1803.6778.02		
Deembedding base option	R&S®RTO6-K121	1801.6887.02		
Embedding and equalization	R&S®RTO6-K126	1801.8109.02		
Video raster analysis	R&S®RTO6-K129	1801.8609.02		
TDR/TDT analysis	R&S®RTO6-K130	1801.6893.02		
Advanced jitter analysis	R&S®RTO6-K133	1801.6906.02		
Advanced noise analysis	R&S®RTO6-K134	1801.7677.02		
PAM-N analysis	R&S®RTO6-K135	1801.8050.02		
Advanced eye analysis	R&S®RTO6-K136	1801.8080.02		
EMC/ESD test	R&S®RTO6-K155	1801.8696.02		
Health and utilization monitoring service (HUMS)	R&S®RTO6-K980	1801.8821.02		

Designation	Type	Order No.		
Step 6: choose compliance test software options			**Test fixture set**	
USB 2.0 compliance test	R&S®RTO6-K21	1801.6912.02	R&S®RT-ZF1	
Ethernet compliance test (10/100/1000BASE-T/EE)	R&S®RTO6-K22	1801.6929.02	R&S®RT-ZF2	
Ethernet compliance test (2.5/5/10GBASE-T)	R&S®RTO6-K23	1801.6935.02	R&S®RT-ZF2	
IEEE 100BASE-T1 compliance test	R&S®RTO6-K24	1801.6941.02	R&S®RT-ZF8, R&S®RT-ZF7A or R&S®RT-ZF2, R&S®RT-ZF3	
MIPI D-PHY compliance test	R&S®RTO6-K26	1801.6958.02	–	
MIPI D-PHY 2.5 compliance test	R&S®RTO6-K27	1803.6578.02		
PCI Express 1.1/2.0 compliance test	R&S®RTO6-K81	1801.6964.02	–	
IEEE 1000BASE-T1 compliance test	R&S®RTO6-K87	1801.6970.02	R&S®RT-ZF8, R&S®RT-ZF7A or R&S®RT-ZF2, R&S®RT-ZF6	
Ethernet compliance test (MGBASE-T1)	R&S®RTO6-K88	1801.7890.02		
IEEE 10BASE-T1 compliance test	R&S®RTO6-K89	1801.6987.02	R&S®RT-ZF7A, R&S®RT-ZF7P or R&S®RT-ZF8	
DDR3/DDR3L/LPDDR3 signal integrity debug and compliance test	R&S®RTO6-K91	1801.6993.02	–	
eMMC compliance test	R&S®RTO6-K92	1801.7160.02	–	
R&S®ScopeSuite automation	R&S®RTO6-K99	1326.4419.02	–	
Step 7: choose signal analysis software and options			**Waveform mode**	**I/Q mode [1)]**
Baseband I/Q analysis	R&S®VSE		●	●
Pulse measurements	R&S®VSE-K6	1320.7516.03	●	●
Multichannel pulse analysis	R&S®VSE-K6a	1345.1286.03	●	●
Modulation analysis of AM/FM/PM modulated single carriers	R&S®VSE-K7	1320.7539.02	●	●
Bluetooth® BR/EDR and Bluetooth® Low Energy measurements	R&S®VSE-K8	1345.1970.02	●	●
Bluetooth® 6.0 Low Energy Channel Sounding measurements	R&S®VSE-K8E	1345.2982.02	●	●
GSM/EDGE/EDGE Evolution signal analysis	R&S®VSE-K10	1320.7574.03		●
Transient analysis	R&S®VSE-K60	1320.7868.03	●	●
Analysis of digitally modulated signals	R&S®VSE-K70	1320.7522.02	●	●
3GPP WCDMA uplink and downlink signal analysis,including HSDPA, HSUPA and HSPA+	R&S®VSE-K72	1320.7580.02		●
WLAN signal analysis, in line with the WLAN IEEE 802.11a/b/be/bn/g/n/p/ac/ax standards	R&S®VSE-K91	1320.7597.02		●
WLAN OFDM cross-correlation	R&S®VSE-K91X	1345.2724.02		●
Analysis of user-defined OFDM and OFDMA signals	R&S®VSE-K96	1320.7922.03	●	●
LTE and LTE advanced signal analysis	R&S®VSE-K100	1320.7545.02		●
LTE and LTE advanced signal analysis	R&S®VSE-K102	1320.7551.03		●
LTE and LTE advanced signal analysis	R&S®VSE-K104	1320.7568.02		●
LTE narrowband IoT analysis	R&S®VSE-K106	1320.7900.03		●
5G signal analysis	R&S®VSE-K144	1309.9574.03		●
3GPP 5G NR cross-correlation	R&S®VSE-K144X	1345.2718.02		●
5G NR MIMO downlink signal analysis	R&S®VSE-K146	1345.1305.02		●
3GPP 5G NR Release 16 extension for uplink/downlink	R&S®VSE-K148	1345.1392.02		●
HRP UWB measurements	R&S®VSE-K149	1345.1463.02	●	●
3GPP 5G NR Release 17 extension for uplink/downlink	R&S®VSE-K171	1345.1663.02		●
O-RAN measurements	R&S®VSE-K175	1350.7020.02		●
Beyond 5G measurements	R&S®VSE-K184	1345.3037.02		●
OneWeb reverse link	R&S®VSE-K201	1345.2018.02	●	●
Software maintenance	R&S®VSE-SWM	1320.7622.81		

[1)] Requires R&S®RTO-K11.

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Designation	Type	Order No.		
Step 8: choose probes and accessories				
Standard accessories: 4 × R&S®RT-ZP10 passive probe, quick start guide, power cord, accessories bag				
Additional probes: See probes and accessories for Rohde & Schwarz oscilloscopes (PD 3606.8866.12)				
Precision BNC to SMA adapter	R&S®RT-ZA16	1320.7074.02		
High-precision and low-loss matched cable pair, length: 1 m	R&S®RT-ZA17	1337.8991.02		
Front cover	R&S®RTO6-Z1	1801.6641.02		
Carrying case	R&S®RTO6-Z3	1801.6658.02		
Transit case	R&S®RTO6-Z4	1801.6712.02		
19" rackmount kit	R&S®ZZA-RTO6	1801.6729.02		

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	SERVICE PLANS	ON DEMAND
Calibration	Up to five years [1]	Pay per calibration
Warranty and repair	Up to five years [1]	Standard price repair

[1] For extended periods, contact your Rohde & Schwarz sales office.

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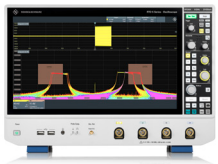
OSCILLOSCOPE PORTFOLIO

	R&S®RTH1000	R&S®RTC1000	R&S®RTB 2	MXO 3
Vertical system				
Bandwidth [1]	60/100/200/350/500 MHz	50/70/100/200/300 MHz	70/100/200/300 MHz	100/200/350/500 MHz/1 GHz
Number of channels	2 plus DMM/4	2	2/4	4/8
Vertical resolution; system architecture	10 bit; 16 bit	8 bit; 16 bit	10 bit; 16 bit	12 bit; 18 bit
V/div, 1 MΩ	2 mV to 100 V	1 mV to 10 V	1 mV to 5 V	1 mV to 10 V
V/div, 50 Ω	–			1 mV to 1 V
Digital channels	8	8	16	16
Horizontal system				
Sampling rate per channel (in Gsample/s)	1.25 (4-channel model); 2.5 (2-channel model); 5 (all channels interleaved)	1; 2 (2 channels interleaved)	1.25; 2.5 (2 channels interleaved)	2.5; 5 (2 channels interleaved)
Maximum memory (per channel; 1 channel active)	125 kpoints (4-channel model); 250 kpoints (2-channel model); 500 kpoints	1 Mpoints; 2 Mpoints	10 Mpoints; 20 Mpoints	standard: 125 Mpoints; max. upgrade: 500 Mpoints [2]
Segmented memory	standard, 50 Mpoints	–	standard, 160 Mpoints	standard: 10 000 segments; option: 1 000 000 segments
Acquisition rate (in waveforms/s)	50 000	10 000	50 000 (300 000 in fast segmented memory mode)	> 4 500 000
Trigger				
Types	digital	analog	analog	advanced (includes zone trigger), digital trigger (15 trigger types)
Sensitivity	–	–	at 1 mV/div: > 2 div	0.0001 div, across full bandwidth, user controllable
Analysis				
Mask test	tolerance mask	tolerance mask	tolerance mask	user configurable, hardware based, tolerance mask
Mathematics	elementary	elementary	basic (math on math)	advanced (formula editor)
Serial protocols triggering and decoding [1]	I²C, SPI, UART/RS-232/RS-422/RS-485, CAN, LIN, CAN FD, SENT	I²C, SPI, UART/RS-232/RS-422/RS-485, CAN, LIN	I²C, SPI, UART/RS-232/RS-422/RS-485, CAN, LIN	I²C, SPI, UART/RS-232/RS-422/RS-485, CAN, CAN FD, CAN XL, LIN, ARINC 429, MIL-STD-1553, SPMI, 10BASE-T1S, QUAD-SPI, OCTO-SPI, SENT, RFFE I³C, NRZ, Manchester, SpaceWire, USB 1.1/2.0
Applications [1, 2]	high-resolution frequency counter, advanced spectrum analysis, harmonics analysis, user scripting	digital voltmeter (DVM), component tester, fast Fourier transform (FFT)	digital voltmeter (DVM), fast Fourier transform (FFT), frequency response analysis	power, digital voltmeter (DVM), frequency response analysis, basic jitter analysis, 3-phase analysis, impedance analysis
Compliance testing [1, 2]	–	–	–	–
Display and operation				
Size and resolution	7" touchscreen, 800 × 480 pixel	6.5", 640 × 480 pixel	10.1" touchscreen, 1280 × 800 pixel	11.6" touchscreen, 1920 × 1080 pixel (Full HD)
General data				
Dimensions in mm (W × H × D)	201 × 293 × 74	285 × 175 × 140	390 × 220 × 152	375 × 233 × 163
Weight in kg	2.4	1.7	2.5	4
Battery	lithium-ion, > 4 h	–	–	–

[1] Upgradeable. [2] Requires an option.



MXO 4	MXO 5/MXO 5C	R&S®RTO6	R&S®RTP
200/350/500 MHz/1/1.5 GHz	100/200/350/500 MHz/1/2 GHz	600 MHz/1/2/3/4/6 GHz	4/6/8/13/16 GHz
4	4/8	4	4
12 bit; 18 bit	12 bit; 18 bit	8 bit; 16 bit	8 bit; 16 bit
500 µV to 10 V	500 µV to 10 V	1 mV to 10 V (HD mode: 500 µV to 10 V)	
500 µV to 1 V	500 µV to 1 V	1 mV to 1 V (HD mode: 500 µV to 1 V)	2 mV to 1 V (HD mode: 1 mV to 1 V)
16	16	16	16
2.5; 5 (2 channels interleaved)	5 on 4 channels; 2.5 on 8 channels (2 channels interleaved)	10; 20 (2 channels interleaved in 4 GHz and 6 GHz model)	20; 40 (2 channels interleaved)
standard: 400 Mpoints; max. upgrade: 800 Mpoints [2)]	standard: 500 Mpoints max. upgrade: 1 Gpoints [2)]	standard: 200 Mpoints/800 Mpoints; max. upgrade: 1 Gpoints/2 Gpoints	standard: 100 Mpoints/400 Mpoints; max. upgrade: 3 Gpoints
standard: 10000 segments; option: 1000000 segments	standard: 10000 segments; option: 1000000 segments	standard	standard
> 4500000	> 4500000	1000000 (2500000 in ultra-segmented memory mode)	750000 (> 3000000 in ultra-segmented memory mode)
advanced (includes zone trigger), digital trigger (15 trigger types)	advanced (includes zone trigger), digital trigger (15 trigger types)	advanced (includes zone trigger), digital trigger (15 trigger types), high speed serial pattern trigger including 5 Gbit/s clock data recovery (CDR) [2)]	advanced (includes zone trigger), digital trigger (14 trigger types) with real-time deembedding [2)], high speed serial pattern trigger including 8/16 Gbit/s clock data recovery (CDR) [2)]
0.0001 div, across full bandwidth, user controllable	0.0001 div, across full bandwidth, user controllable	0.0001 div, across full bandwidth, user controllable	0.0001 div, across full bandwidth, user controllable
user configurable, hardware based, tolerance mask	user configurable, hardware based, tolerance mask	user configurable, hardware based	user configurable, hardware based
advanced (formula editor)	advanced (formula editor)	advanced (formula editor, Python interface)	advanced (formula editor, Python interface)
I²C, SPI, UART/RS-232/RS-422/RS-485, CAN, CAN FD, CAN XL, LIN, ARINC 429, MIL-STD-1553, SPMI, 10BASE-T1S, QUAD-SPI, OCTO-SPI, SENT, RFFE, I³C, NRZ, Manchester, SpaceWire, USB 1.1/2.0	I²C, SPI, UART/RS-232/RS-422/RS-485, CAN, CAN FD, CAN XL, LIN, ARINC 429, MIL-STD-1553, SPMI, 10BASE-T1S, 100/1000BASE-T1, QUAD-SPI, OCTO-SPI, 8b10b, SENT, RFFE, I³C, NRZ, Manchester, SpaceWire, USB 1.1/2.0, MIPI D-PHY (CSI2/DSI)	I²C, SPI, UART/RS-232/RS-422/RS-485, CAN, LIN, I²S, MIL-STD-1553, ARINC 429, FlexRay, CAN FD, CAN XL, MIPI RFFE, USB 2.0/HSIC, MDIO, 8b10b, Ethernet, Manchester, NRZ, SENT, MIPI D-PHY, SpaceWire, MIPI M-PHY/UniPro, CXPI, USB 3.1 Gen 1, USB-SSIC, PCIe 1.1/2.0, USB Power Delivery, Automotive Ethernet 10BASE-T1S, 100/1000BASE-T1, I³C	I²C, SPI, UART/RS-232/RS-422/RS-485, SENT, CAN, LIN, CAN FD, CAN XL, MIL-STD-1553, ARINC 429, SpaceWire, USB 2.0/HSIC/PD, USB 3.1 Gen 1/Gen 2/SSIC, PCIe 1.1/2.0/3.0, 8b10b, MIPI RFFE, MIPI D/M-PHY/UniPro, Automotive Ethernet 10BASE-T1S, 100/1000BASE-T1, Ethernet 10/100BASE-TX, MDIO, Manchester, NRZ, I³C
power, digital voltmeter (DVM), frequency response analysis, basic jitter analysis, 3-phase analysis, impedance analysis	power, digital voltmeter (DVM), frequency response analysis, basic jitter analysis, eye analysis, 3-phase analysis, impedance analysis	power, advanced spectrum analysis and spectrogram, jitter and noise decomposition, clock data recovery (CDR), I/Q data and RF analysis (R&S®VSE), deembedding, embedding, equalization, PAM-N, TDR/TDT analysis, advanced eye diagram, EMC/ESD test	advanced spectrum analysis and spectrogram, jitter and noise decomposition, real-time deembedding, embedding, equalization, PAM-N, TDR/TDT analysis, I/Q data and RF analysis (R&S®VSE), advanced eye diagram, EMC/ESD test
–	see specifications (PD 3683.8196.22, PD 3684.1472.22)	see specifications (PD 5216.1640.22)	see specifications (PD 3683.5616.22)
13.3" touchscreen, 1920 × 1080 pixel (Full HD)	for MXO 5 only: 15.6" touchscreen, 1920 × 1080 pixel (Full HD)	15.6" touchscreen, 1920 × 1080 pixel (Full HD)	13.3" touchscreen, 1920 × 1080 pixel (Full HD)
414 × 279 × 162	MXO 5: 445 × 314 × 154 MXO 5C: 445 × 105 × 405	450 × 315 × 204	441 × 285 × 316
6	MXO 5: 9 MXO 5C: 8.7	10.7	18
–	–	–	–

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